



# HIGH-SPEED 3.3V 512K x 18 SYNCHRONOUS BANK-SWITCHABLE DUAL-PORT STATIC RAM WITH 3.3V OR 2.5V INTERFACE

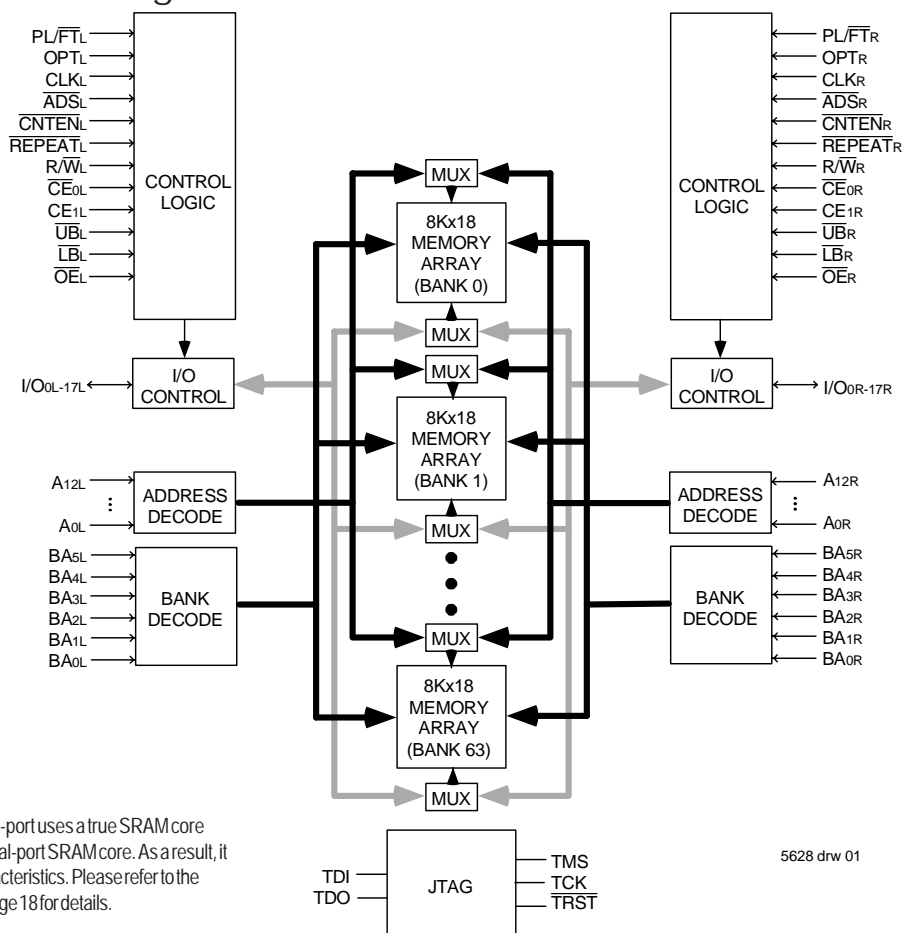
**IDT70V7339S**

LEAD FINISH (SnPb) ARE IN EOL PROCESS - LAST TIME BUY EXPIRES JUNE 15, 2018

## Features:

- ♦ 512K x 18 Synchronous Bank-Switchable Dual-ported SRAM Architecture
  - 64 independent 8K x 18 banks
  - 9 megabits of memory on chip
- ♦ Bank access controlled via bank address pins
- ♦ High-speed data access
  - Commercial: 3.4ns (200MHz)/3.6ns (166MHz)/4.2ns (133MHz) (max.)
  - Industrial: 3.6ns (166MHz)/4.2ns (133MHz) (max.)
- ♦ Selectable Pipelined or Flow-Through output mode
- ♦ Counter enable and repeat features
- ♦ Dual chip enables allow for depth expansion without additional logic
- ♦ Full synchronous operation on both ports
  - 5ns cycle time, 200MHz operation (14Gbps bandwidth)
  - Fast 3.4ns clock to data out
- 1.5ns setup to clock and 0.5ns hold on all control, data, and address inputs @ 200MHz
- Data input, address, byte enable and control registers
- Self-timed write allows fast cycle time
- ♦ Separate byte controls for multiplexed bus and bus matching compatibility
- ♦ LVTTTL-compatible, 3.3V ( $\pm 150\text{mV}$ ) power supply for core
- ♦ LVTTTL compatible, selectable 3.3V ( $\pm 150\text{mV}$ ) or 2.5V ( $\pm 100\text{mV}$ ) power supply for I/Os and control signals on each port
- ♦ Industrial temperature range ( $-40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ ) is available at 166MHz and 133MHz
- ♦ Available in 208-pin fine pitch Ball Grid Array (fpBGA) and 256-pin Ball Grid Array (BGA)
- ♦ Supports JTAG features compliant with IEEE 1149.1
- ♦ Green parts available, see ordering information

## Functional Block Diagram



### NOTE:

1. The Bank-Switchable dual-port uses a true SRAM core instead of the traditional dual-port SRAM core. As a result, it has unique operating characteristics. Please refer to the functional description on page 18 for details.

JUNE 2018

## Description:

The IDT70V7339 is a high-speed 512Kx18 (9Mbit) synchronous Bank-Switchable Dual-Ported SRAM organized into 64 independent 8Kx18 banks. The device has two independent ports with separate control, address, and I/O pins for each port, allowing each port to access any 8Kx18 memory block not already accessed by the other port. Accesses by the ports into specific banks are controlled via the bank address pins under the user's direct control.

Registers on control, data, and address inputs provide minimal setup and hold times. The timing latitude provided by this approach allows systems to be designed with very short cycle times. With an input data

register, the IDT70V7339 has been optimized for applications having unidirectional or bidirectional data flow in bursts. An automatic power down feature, controlled by CE<sub>0</sub> and CE<sub>1</sub>, permits the on-chip circuitry of each port to enter a very low standby power mode. The dual chip enables also facilitate depth expansion.

The 70V7339 can support an operating voltage of either 3.3V or 2.5V on one or both ports, controllable by the OPT pins. The power supply for the core of the device (V<sub>DD</sub>) remains at 3.3V. Please refer also to the functional description on page 18.

## Pin Configuration<sup>(1,2,3,4)</sup>

A1 IO <sub>9L</sub>	A2 NC	A3 VSS	A4 TDO	A5 NC	A6 BA <sub>3L</sub>	A7 A <sub>12L</sub>	A8 A <sub>8L</sub>	A9 NC	A10 VDD	A11 CLK <sub>L</sub>	A12 CNTEN <sub>L</sub>	A13 A <sub>4L</sub>	A14 A <sub>0L</sub>	A15 OPT <sub>L</sub>	A16 NC	A17 VSS	
B1 NC	B2 VSS	B3 NC	B4 TDI	B5 BA <sub>4L</sub>	B6 BA <sub>0L</sub>	B7 A <sub>9L</sub>	B8 NC	B9 CE <sub>0L</sub>	B10 VSS	B11 AD <sub>S</sub> <sub>L</sub>	B12 A <sub>5L</sub>	B13 A <sub>1L</sub>	B14 VSS	B15 VDDQ <sub>R</sub>	B16 IO <sub>8L</sub>	B17 NC	
C1 VDDQ <sub>L</sub>	C2 IO <sub>9R</sub>	C3 VDDQ <sub>R</sub>	C4 PL/FT <sub>L</sub>	C5 BA <sub>5L</sub>	C6 BA <sub>1L</sub>	C7 A <sub>10L</sub>	C8 UB <sub>L</sub>	C9 CE <sub>1L</sub>	C10 VSS	C11 R/W <sub>L</sub>	C12 A <sub>6L</sub>	C13 A <sub>2L</sub>	C14 VDD	C15 IO <sub>8R</sub>	C16 NC	C17 VSS	
D1 NC	D2 VSS	D3 IO <sub>10L</sub>	D4 NC	D5 BA <sub>2L</sub>	D6 A <sub>11L</sub>	D7 A <sub>7L</sub>	D8 LB <sub>L</sub>	D9 VDD	D10 OEL	D11 REPEAT <sub>L</sub>	D12 A <sub>3L</sub>	D13 VDD	D14 NC	D15 VDDQ <sub>L</sub>	D16 IO <sub>7L</sub>	D17 IO <sub>7R</sub>	
E1 IO <sub>11L</sub>	E2 NC	E3 VDDQ <sub>R</sub>	E4 IO <sub>10R</sub>	<div>70V7339BF BF-208<sup>(5)</sup>  208-Pin fpBGA Top View<sup>(6)</sup></div>										E14 IO <sub>6L</sub>	E15 NC	E16 VSS	E17 NC
F1 VDDQ <sub>L</sub>	F2 IO <sub>11R</sub>	F3 NC	F4 VSS											F14 VSS	F15 IO <sub>6R</sub>	F16 NC	F17 VDDQ <sub>R</sub>
G1 NC	G2 VSS	G3 IO <sub>12L</sub>	G4 NC											G14 NC	G15 VDDQ <sub>L</sub>	G16 IO <sub>5L</sub>	G17 NC
H1 VDD	H2 NC	H3 VDDQ <sub>R</sub>	H4 IO <sub>12R</sub>											H14 VDD	H15 NC	H16 VSS	H17 IO <sub>5R</sub>
J1 VDDQ <sub>L</sub>	J2 VDD	J3 VSS	J4 VSS											J14 VSS	J15 VDD	J16 VSS	J17 VDDQ <sub>R</sub>
K1 IO <sub>14R</sub>	K2 VSS	K3 IO <sub>13R</sub>	K4 VSS											K14 IO <sub>3R</sub>	K15 VDDQ <sub>L</sub>	K16 IO <sub>4R</sub>	K17 VSS
L1 NC	L2 IO <sub>14L</sub>	L3 VDDQ <sub>R</sub>	L4 IO <sub>13L</sub>											L14 NC	L15 IO <sub>3L</sub>	L16 VSS	L17 IO <sub>4L</sub>
M1 VDDQ <sub>L</sub>	M2 NC	M3 IO <sub>15R</sub>	M4 VSS											M14 VSS	M15 NC	M16 IO <sub>2R</sub>	M17 VDDQ <sub>R</sub>
N1 NC	N2 VSS	N3 NC	N4 IO <sub>15L</sub>	N14 IO <sub>1R</sub>	N15 VDDQ <sub>L</sub>	N16 NC	N17 IO <sub>2L</sub>										
P1 IO <sub>16R</sub>	P2 IO <sub>16L</sub>	P3 VDDQ <sub>R</sub>	P4 NC	P5 TRST	P6 BA <sub>3R</sub>	P7 A <sub>12R</sub>	P8 A <sub>8R</sub>	P9 NC	P10 VDD	P11 CLK <sub>R</sub>	P12 CNTEN <sub>R</sub>	P13 A <sub>4R</sub>	P14 NC	P15 IO <sub>1L</sub>	P16 VSS	P17 NC	
R1 VSS	R2 NC	R3 IO <sub>17R</sub>	R4 TCK	R5 BA <sub>4R</sub>	R6 BA <sub>0R</sub>	R7 A <sub>9R</sub>	R8 NC	R9 CE <sub>0R</sub>	R10 VSS	R11 AD <sub>S</sub> <sub>R</sub>	R12 A <sub>5R</sub>	R13 A <sub>1R</sub>	R14 VSS	R15 VDDQ <sub>L</sub>	R16 IO <sub>0R</sub>	R17 VDDQ <sub>R</sub>	
T1 NC	T2 IO <sub>17L</sub>	T3 VDDQ <sub>L</sub>	T4 TMS	T5 BA <sub>5R</sub>	T6 BA <sub>1R</sub>	T7 A <sub>10R</sub>	T8 UB <sub>R</sub>	T9 CE <sub>1R</sub>	T10 VSS	T11 R/W <sub>R</sub>	T12 A <sub>6R</sub>	T13 A <sub>2R</sub>	T14 VSS	T15 NC	T16 VSS	T17 NC	
U1 VSS	U2 NC	U3 PL/FT <sub>R</sub>	U4 NC	U5 BA <sub>2R</sub>	U6 A <sub>11R</sub>	U7 A <sub>7R</sub>	U8 LB <sub>R</sub>	U9 VDD	U10 OER	U11 REPEAT <sub>R</sub>	U12 A <sub>3R</sub>	U13 A <sub>0R</sub>	U14 VDD	U15 OPT <sub>R</sub>	U16 NC	U17 IO <sub>0L</sub>	

### NOTES:

- All V<sub>DD</sub> pins must be connected to 3.3V power supply.
- All V<sub>DDQ</sub> pins must be connected to appropriate power supply: 3.3V if OPT pin for that port is set to V<sub>IH</sub> (3.3V), and 2.5V if OPT pin for that port is set to V<sub>IL</sub> (0V).
- All V<sub>SS</sub> pins must be connected to ground supply.
- Package body is approximately 15mm x 15mm x 1.4mm with 0.8mm ball pitch.
- This package code is used to reference the package diagram.
- This text does not indicate orientation of the actual part-marking.

5628 drw 02c

Pin Configuration<sup>(1,2,3,4)</sup> (con't.)

70V7339BC

BC-256<sup>(5)</sup>

256-Pin BGA

Top View<sup>(6)</sup>

A1 NC	A2 TDI	A3 NC	A4 BA <sub>4L</sub>	A5 BA <sub>1L</sub>	A6 A <sub>11L</sub>	A7 A <sub>8L</sub>	A8 NC	A9 CE <sub>1L</sub>	A10 OE <sub>L</sub>	A11 CNTEN <sub>L</sub>	A12 A <sub>5L</sub>	A13 A <sub>2L</sub>	A14 A <sub>0L</sub>	A15 NC	A16 NC
B1 NC	B2 NC	B3 TDO	B4 BA <sub>5L</sub>	B5 BA <sub>2L</sub>	B6 A <sub>12L</sub>	B7 A <sub>9L</sub>	B8 UB <sub>L</sub>	B9 CE <sub>0L</sub>	B10 R/W <sub>L</sub>	B11 REPEAT <sub>L</sub>	B12 A <sub>4L</sub>	B13 A <sub>1L</sub>	B14 V <sub>DD</sub>	B15 NC	B16 NC
C1 NC	C2 I/O <sub>9L</sub>	C3 V <sub>SS</sub>	C4 BA <sub>3L</sub>	C5 BA <sub>0L</sub>	C6 A <sub>10L</sub>	C7 A <sub>7L</sub>	C8 NC	C9 LB <sub>L</sub>	C10 CLK <sub>L</sub>	C11 AD <sub>S</sub> <sub>L</sub>	C12 A <sub>6L</sub>	C13 A <sub>3L</sub>	C14 OPT <sub>L</sub>	C15 NC	C16 I/O <sub>8L</sub>
D1 NC	D2 I/O <sub>9R</sub>	D3 NC	D4 PL/FT <sub>L</sub>	D5 V <sub>DDQL</sub>	D6 V <sub>DDQL</sub>	D7 V <sub>DDQR</sub>	D8 V <sub>DDQR</sub>	D9 V <sub>DDQL</sub>	D10 V <sub>DDQL</sub>	D11 V <sub>DDQR</sub>	D12 V <sub>DDQR</sub>	D13 V <sub>DD</sub>	D14 NC	D15 NC	D16 I/O <sub>8R</sub>
E1 I/O <sub>10R</sub>	E2 I/O <sub>10L</sub>	E3 NC	E4 V <sub>DDQL</sub>	E5 V <sub>DD</sub>	E6 V <sub>DD</sub>	E7 V <sub>SS</sub>	E8 V <sub>SS</sub>	E9 V <sub>SS</sub>	E10 V <sub>SS</sub>	E11 V <sub>DD</sub>	E12 V <sub>DD</sub>	E13 V <sub>DDQR</sub>	E14 NC	E15 I/O <sub>7L</sub>	E16 I/O <sub>7R</sub>
F1 I/O <sub>11L</sub>	F2 NC	F3 I/O <sub>11R</sub>	F4 V <sub>DDQL</sub>	F5 V <sub>DD</sub>	F6 V <sub>SS</sub>	F7 V <sub>SS</sub>	F8 V <sub>SS</sub>	F9 V <sub>SS</sub>	F10 V <sub>SS</sub>	F11 V <sub>SS</sub>	F12 V <sub>DD</sub>	F13 V <sub>DDQR</sub>	F14 I/O <sub>6R</sub>	F15 NC	F16 I/O <sub>6L</sub>
G1 NC	G2 NC	G3 I/O <sub>12L</sub>	G4 V <sub>DDQR</sub>	G5 V <sub>SS</sub>	G6 V <sub>SS</sub>	G7 V <sub>SS</sub>	G8 V <sub>SS</sub>	G9 V <sub>SS</sub>	G10 V <sub>SS</sub>	G11 V <sub>SS</sub>	G12 V <sub>SS</sub>	G13 V <sub>DDQL</sub>	G14 I/O <sub>5L</sub>	G15 NC	G16 NC
H1 NC	H2 I/O <sub>12R</sub>	H3 NC	H4 V <sub>DDQR</sub>	H5 V <sub>SS</sub>	H6 V <sub>SS</sub>	H7 V <sub>SS</sub>	H8 V <sub>SS</sub>	H9 V <sub>SS</sub>	H10 V <sub>SS</sub>	H11 V <sub>SS</sub>	H12 V <sub>SS</sub>	H13 V <sub>DDQL</sub>	H14 NC	H15 NC	H16 I/O <sub>5R</sub>
J1 I/O <sub>13L</sub>	J2 I/O <sub>14R</sub>	J3 I/O <sub>13R</sub>	J4 V <sub>DDQL</sub>	J5 V <sub>SS</sub>	J6 V <sub>SS</sub>	J7 V <sub>SS</sub>	J8 V <sub>SS</sub>	J9 V <sub>SS</sub>	J10 V <sub>SS</sub>	J11 V <sub>SS</sub>	J12 V <sub>SS</sub>	J13 V <sub>DDQR</sub>	J14 I/O <sub>4R</sub>	J15 I/O <sub>3R</sub>	J16 I/O <sub>4L</sub>
K1 NC	K2 NC	K3 I/O <sub>14L</sub>	K4 V <sub>DDQL</sub>	K5 V <sub>SS</sub>	K6 V <sub>SS</sub>	K7 V <sub>SS</sub>	K8 V <sub>SS</sub>	K9 V <sub>SS</sub>	K10 V <sub>SS</sub>	K11 V <sub>SS</sub>	K12 V <sub>SS</sub>	K13 V <sub>DDQR</sub>	K14 NC	K15 NC	K16 I/O <sub>3L</sub>
L1 I/O <sub>15L</sub>	L2 NC	L3 I/O <sub>15R</sub>	L4 V <sub>DDQR</sub>	L5 V <sub>DD</sub>	L6 V <sub>SS</sub>	L7 V <sub>SS</sub>	L8 V <sub>SS</sub>	L9 V <sub>SS</sub>	L10 V <sub>SS</sub>	L11 V <sub>SS</sub>	L12 V <sub>DD</sub>	L13 V <sub>DDQL</sub>	L14 I/O <sub>2L</sub>	L15 NC	L16 I/O <sub>2R</sub>
M1 I/O <sub>16R</sub>	M2 I/O <sub>16L</sub>	M3 NC	M4 V <sub>DDQR</sub>	M5 V <sub>DD</sub>	M6 V <sub>DD</sub>	M7 V <sub>SS</sub>	M8 V <sub>SS</sub>	M9 V <sub>SS</sub>	M10 V <sub>SS</sub>	M11 V <sub>DD</sub>	M12 V <sub>DD</sub>	M13 V <sub>DDQL</sub>	M14 I/O <sub>1R</sub>	M15 I/O <sub>1L</sub>	M16 NC
N1 NC	N2 I/O <sub>17R</sub>	N3 NC	N4 PL/FT <sub>R</sub>	N5 V <sub>DDQR</sub>	N6 V <sub>DDQR</sub>	N7 V <sub>DDQL</sub>	N8 V <sub>DDQL</sub>	N9 V <sub>DDQR</sub>	N10 V <sub>DDQR</sub>	N11 V <sub>DDQL</sub>	N12 V <sub>DDQL</sub>	N13 V <sub>DD</sub>	N14 NC	N15 I/O <sub>0R</sub>	N16 NC
P1 NC	P2 I/O <sub>17L</sub>	P3 TMS	P4 BA <sub>3R</sub>	P5 BA <sub>0R</sub>	P6 A <sub>10R</sub>	P7 A <sub>7R</sub>	P8 NC	P9 LB <sub>R</sub>	P10 CLK <sub>R</sub>	P11 AD <sub>S</sub> <sub>R</sub>	P12 A <sub>6R</sub>	P13 A <sub>3R</sub>	P14 NC	P15 NC	P16 I/O <sub>0L</sub>
R1 NC	R2 NC	R3 TRST	R4 BA <sub>5R</sub>	R5 BA <sub>2R</sub>	R6 A <sub>12R</sub>	R7 A <sub>9R</sub>	R8 UB <sub>R</sub>	R9 CE <sub>0R</sub>	R10 R/W <sub>R</sub>	R11 REPEAT <sub>R</sub>	R12 A <sub>4R</sub>	R13 A <sub>1R</sub>	R14 OPT <sub>R</sub>	R15 NC	R16 NC
T1 NC	T2 TCK	T3 NC	T4 BA <sub>4R</sub>	T5 BA <sub>1R</sub>	T6 A <sub>11R</sub>	T7 A <sub>8R</sub>	T8 NC	T9 CE <sub>1R</sub>	T10 OE <sub>R</sub>	T11 CNTEN <sub>R</sub>	T12 A <sub>5R</sub>	T13 A <sub>2R</sub>	T14 A <sub>0R</sub>	T15 NC	T16 NC

## NOTES:

5628 drw 02d

1. All V<sub>DD</sub> pins must be connected to 3.3V power supply.
2. All V<sub>DDQ</sub> pins must be connected to appropriate power supply: 3.3V if OPT pin for that port is set to V<sub>IH</sub> (3.3V), and 2.5V if OPT pin for that port is set to V<sub>IL</sub> (0V).
3. All V<sub>SS</sub> pins must be connected to ground supply.
4. Package body is approximately 17mm x 17mm x 1.4mm, with 1.0mm ball-pitch.
5. This package code is used to reference the package diagram.
6. This text does not indicate orientation of the actual part-marking.

## Pin Names

Left Port	Right Port	Names
$\overline{CE}_{0L}$ , $CE_{1L}$	$\overline{CE}_{0R}$ , $CE_{1R}$	Chip Enables
$R/\overline{WL}$	$R/\overline{WR}$	Read/Write Enable
$\overline{OE}_L$	$\overline{OE}_R$	Output Enable
$BA_{0L}$ - $BA_{5L}$	$BA_{0R}$ - $BA_{5R}$	Bank Address <sup>(4)</sup>
$A_{0L}$ - $A_{12L}$	$A_{0R}$ - $A_{12R}$	Address
$I/O_{0L}$ - $I/O_{17L}$	$I/O_{0R}$ - $I/O_{17R}$	Data Input/Output
$CLK_L$	$CLK_R$	Clock
$PL/\overline{FT}_L$	$PL/\overline{FT}_R$	Pipeline/Flow-Through
$\overline{ADS}_L$	$\overline{ADS}_R$	Address Strobe Enable
$\overline{CNTEN}_L$	$\overline{CNTEN}_R$	Counter Enable
$\overline{REPEAT}_L$	$\overline{REPEAT}_R$	Counter Repeat <sup>(3)</sup>
$\overline{LB}_L$ , $\overline{UB}_L$	$\overline{LB}_R$ , $\overline{UB}_R$	Byte Enables (9-bit bytes)
$V_{DDOL}$	$V_{DDOR}$	Power (I/O Bus) (3.3V or 2.5V) <sup>(1)</sup>
$OPT_L$	$OPT_R$	Option for selecting $V_{DDOX}$ <sup>(1,2)</sup>
$V_{DD}$		Power (3.3V) <sup>(1)</sup>
$V_{SS}$		Ground (0V)
$TDI$		Test Data Input
$TDO$		Test Data Output
$TCK$		Test Logic Clock (10MHz)
$TMS$		Test Mode Select
$\overline{TRST}$		Reset (Initialize TAP Controller)

5628 tbl 01

## NOTES:

1.  $V_{DD}$ ,  $OPT_x$ , and  $V_{DDOX}$  must be set to appropriate operating levels prior to applying inputs on the I/Os and controls for that port.
2.  $OPT_x$  selects the operating voltage levels for the I/Os and controls on that port. If  $OPT_x$  is set to VIH (3.3V), then that port's I/Os and controls will operate at 3.3V levels and  $V_{DDOX}$  must be supplied at 3.3V. If  $OPT_x$  is set to VIL (0V), then that port's I/Os and address controls will operate at 2.5V levels and  $V_{DDOX}$  must be supplied at 2.5V. The  $OPT$  pins are independent of one another—both ports can operate at 3.3V levels, both can operate at 2.5V levels, or either can operate at 3.3V with the other at 2.5V.
3. When  $\overline{REPEAT}_x$  is asserted, the counter will reset to the last valid address loaded via  $\overline{ADS}_x$ .
4. Accesses by the ports into specific banks are controlled by the bank address pins under the user's direct control: each port can access any bank of memory with the shared array that is not currently being accessed by the opposite port (i.e.,  $BA_{0L}$  -  $BA_{5L} \neq BA_{0R}$  -  $BA_{5R}$ ). In the event that both ports try to access the same bank at the same time, neither access will be valid, and data at the two specific addresses targeted by the ports within that bank may be corrupted (in the case that either or both ports are writing) or may result in invalid output (in the case that both ports are trying to read).

Truth Table I—Read/Write and Enable Control<sup>(1,2,3,4)</sup>

$\overline{OE}^3$	CLK	$\overline{CE}_0$	CE <sub>1</sub>	$\overline{UB}$	$\overline{LB}$	R/ $\overline{W}$	Upper Byte I/O <sub>9-17</sub>	Lower Byte I/O <sub>0-8</sub>	MODE
X	↑	H	X	X	X	X	High-Z	High-Z	Deselected—Power Down
X	↑	X	L	X	X	X	High-Z	High-Z	Deselected—Power Down
X	↑	L	H	H	H	X	High-Z	High-Z	All Bytes Deselected
X	↑	L	H	H	L	L	High-Z	D <sub>IN</sub>	Write to Lower Byte Only
X	↑	L	H	L	H	L	D <sub>IN</sub>	High-Z	Write to Upper Byte Only
X	↑	L	H	L	L	L	D <sub>IN</sub>	D <sub>IN</sub>	Write to both Bytes
L	↑	L	H	H	L	H	High-Z	D <sub>OUT</sub>	Read Lower Byte Only
L	↑	L	H	L	H	H	D <sub>OUT</sub>	High-Z	Read Upper Byte Only
L	↑	L	H	L	L	H	D <sub>OUT</sub>	D <sub>OUT</sub>	Read both Bytes
H	X	X	X	X	X	X	High-Z	High-Z	Outputs Disabled

5628 tbl 02

## NOTES:

- "H" = V<sub>IH</sub>, "L" = V<sub>IL</sub>, "X" = Don't Care.
- $\overline{ADS}$ ,  $\overline{CNTEN}$ ,  $\overline{REPEAT}$  are set as appropriate for address access. Refer to Truth Table II for details.
- $\overline{OE}$  is an asynchronous input signal.
- It is possible to read or write any combination of bytes during a given access. A few representative samples have been illustrated here.

Truth Table II—Address and Address Counter Control<sup>(1,2,7)</sup>

Address	Previous Address	Addr Used	CLK	$\overline{ADS}$	$\overline{CNTEN}$	$\overline{REPEAT}^{(6)}$	I/O <sup>(8)</sup>	MODE
An	X	An	↑	L <sup>(4)</sup>	X	H	D <sub>IO</sub> (n)	External Address Used
X	An	An + 1	↑	H	L <sup>(5)</sup>	H	D <sub>IO</sub> (n+1)	Counter Enabled—Internal Address generation
X	An + 1	An + 1	↑	H	H	H	D <sub>IO</sub> (n+1)	External Address Blocked—Counter disabled (An + 1 reused)
X	X	An	↑	X	X	L <sup>(4)</sup>	D <sub>IO</sub> (0)	Counter Set to last valid $\overline{ADS}$ load

5628 tbl 03

## NOTES:

- "H" = V<sub>IH</sub>, "L" = V<sub>IL</sub>, "X" = Don't Care.
- Read and write operations are controlled by the appropriate setting of R/ $\overline{W}$ ,  $\overline{CE}_0$ , CE<sub>1</sub>,  $\overline{UB}/\overline{LB}$  and  $\overline{OE}$ .
- Outputs configured in flow-through output mode: if outputs are in pipelined mode the data out will be delayed by one cycle.
- $\overline{ADS}$  and  $\overline{REPEAT}$  are independent of all other memory control signals including  $\overline{CE}_0$ , CE<sub>1</sub> and  $\overline{UB}/\overline{LB}$ .
- The address counter advances if  $\overline{CNTEN}$  = V<sub>IL</sub> on the rising edge of CLK, regardless of all other memory control signals including  $\overline{CE}_0$ , CE<sub>1</sub>,  $\overline{UB}/\overline{LB}$ .
- When  $\overline{REPEAT}$  is asserted, the counter will reset to the last valid address loaded via  $\overline{ADS}$ . This value is not set at power-up: a known location should be loaded via  $\overline{ADS}$  during initialization if desired. Any subsequent  $\overline{ADS}$  access during operations will update the  $\overline{REPEAT}$  address location.
- The counter includes bank address and internal address. The counter will advance across bank boundaries. For example, if the counter is in Bank 0, at address FFFh, and is advanced one location, it will move to address 0h in Bank 1. By the same token, the counter at FFFh in Bank 63 will advance to 0h in Bank 0. Refer to Timing Waveform of Counter Repeat, page 17. Care should be taken during operation to avoid having both counters point to the same bank (i.e., ensure BA<sub>0L</sub> - BA<sub>5L</sub> ≠ BA<sub>0R</sub> - BA<sub>5R</sub>), as this condition will invalidate the access for both ports. Please refer to the functional description on page 18 for details.

## Recommended Operating Temperature and Supply Voltage<sup>(1)</sup>

Grade	Ambient Temperature	GND	V <sub>DD</sub>
Commercial	0°C to +70°C	0V	3.3V $\pm$ 150mV
Industrial	-40°C to +85°C	0V	3.3V $\pm$ 150mV

5628 tbl 04

### NOTE:

1. This is the parameter T<sub>A</sub>. This is the "instant on" case temperature.

## Absolute Maximum Ratings<sup>(1)</sup>

Symbol	Rating	Commercial & Industrial	Unit
V <sub>TERM</sub> <sup>(2)</sup>	Terminal Voltage with Respect to GND	-0.5 to +4.6	V
T <sub>BIAS</sub>	Temperature Under Bias	-55 to +125	°C
T <sub>STG</sub>	Storage Temperature	-65 to +150	°C
I <sub>OUT</sub>	DC Output Current	50	mA

5628 tbl 06

### NOTES:

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
2. V<sub>TERM</sub> must not exceed V<sub>DD</sub> + 150mV for more than 25% of the cycle time or 4ns maximum, and is limited to  $\leq 20$ mA for the period of V<sub>TERM</sub>  $\geq$  V<sub>DD</sub> + 150mV.

## Recommended DC Operating Conditions with V<sub>DDQ</sub> at 2.5V

Symbol	Parameter	Min.	Typ.	Max.	Unit
V <sub>DD</sub>	Core Supply Voltage	3.15	3.3	3.45	V
V <sub>DDQ</sub>	I/O Supply Voltage <sup>(3)</sup>	2.4	2.5	2.6	V
V <sub>SS</sub>	Ground	0	0	0	V
V <sub>IH</sub>	Input High Voltage (Address & Control Inputs)	1.7	—	V <sub>DDQ</sub> + 100mV <sup>(2)</sup>	V
V <sub>IH</sub>	Input High Voltage - I/O <sup>(3)</sup>	1.7	—	V <sub>DDQ</sub> + 100mV <sup>(2)</sup>	V
V <sub>IL</sub>	Input Low Voltage	-0.3 <sup>(1)</sup>	—	0.7	V

5628 tbl 05a

### NOTES:

1. Undershoot of V<sub>IL</sub>  $\geq$  -1.5V for pulse width less than 10ns is allowed.
2. V<sub>TERM</sub> must not exceed V<sub>DDQ</sub> + 100mV.
3. To select operation at 2.5V levels on the I/Os and controls of a given port, the OPT pin for that port must be set to V<sub>IL</sub> (0V), and V<sub>DDQx</sub> for that port must be supplied as indicated above.

## Recommended DC Operating Conditions with V<sub>DDQ</sub> at 3.3V

Symbol	Parameter	Min.	Typ.	Max.	Unit
V <sub>DD</sub>	Core Supply Voltage	3.15	3.3	3.45	V
V <sub>DDQ</sub>	I/O Supply Voltage <sup>(3)</sup>	3.15	3.3	3.45	V
V <sub>SS</sub>	Ground	0	0	0	V
V <sub>IH</sub>	Input High Voltage (Address & Control Inputs) <sup>(3)</sup>	2.0	—	V <sub>DDQ</sub> + 150mV <sup>(2)</sup>	V
V <sub>IH</sub>	Input High Voltage - I/O <sup>(3)</sup>	2.0	—	V <sub>DDQ</sub> + 150mV <sup>(2)</sup>	V
V <sub>IL</sub>	Input Low Voltage	-0.3 <sup>(1)</sup>	—	0.8	V

5628 tbl 05b

### NOTES:

1. Undershoot of V<sub>IL</sub>  $\geq$  -1.5V for pulse width less than 10ns is allowed.
2. V<sub>TERM</sub> must not exceed V<sub>DDQ</sub> + 150mV.
3. To select operation at 3.3V levels on the I/Os and controls of a given port, the OPT pin for that port must be set to V<sub>IH</sub> (3.3V), and V<sub>DDQx</sub> for that port must be supplied as indicated above.

Capacitance<sup>(1)</sup>

(TA = +25°C, F = 1.0MHz) PQFP ONLY

Symbol	Parameter	Conditions <sup>(2)</sup>	Max.	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 3dV	8	pF
C <sub>OUT</sub> <sup>(3)</sup>	Output Capacitance	V <sub>OUT</sub> = 3dV	10.5	pF

5628 tbl 07

## NOTES:

- These parameters are determined by device characterization, but are not production tested.
- 3dV references the interpolated capacitance when the input and output switch from 0V to 3V or from 3V to 0V.
- C<sub>OUT</sub> also references C<sub>I/O</sub>.

DC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range (V<sub>DD</sub> = 3.3V ± 150mV)

Symbol	Parameter	Test Conditions	70V7339S		Unit
			Min.	Max.	
I <sub>LI</sub>	Input Leakage Current <sup>(1)</sup>	V <sub>DDQ</sub> = Max., V <sub>IN</sub> = 0V to V <sub>DDQ</sub>	—	10	μA
I <sub>LO</sub>	Output Leakage Current <sup>(1)</sup>	$\overline{CE}_0 = V_{IH}$ or $CE_1 = V_{IL}$ , V <sub>OUT</sub> = 0V to V <sub>DDQ</sub>	—	10	μA
V <sub>OL</sub> (3.3V)	Output Low Voltage <sup>(2)</sup>	I <sub>OL</sub> = +4mA, V <sub>DDQ</sub> = Min.	—	0.4	V
V <sub>OH</sub> (3.3V)	Output High Voltage <sup>(2)</sup>	I <sub>OH</sub> = -4mA, V <sub>DDQ</sub> = Min.	2.4	—	V
V <sub>OL</sub> (2.5V)	Output Low Voltage <sup>(2)</sup>	I <sub>OL</sub> = +2mA, V <sub>DDQ</sub> = Min.	—	0.4	V
V <sub>OH</sub> (2.5V)	Output High Voltage <sup>(2)</sup>	I <sub>OH</sub> = -2mA, V <sub>DDQ</sub> = Min.	2.0	—	V

5628 tbl 08

## NOTES:

- At V<sub>DD</sub> ≤ 2.0V leakages are undefined.
- V<sub>DDQ</sub> is selectable (3.3V/2.5V) via OPT pins. Refer to page 4 for details.

# DC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range<sup>(5)</sup> ( $V_{DD} = 3.3V \pm 150mV$ )

Symbol	Parameter	Test Condition	Version	70V7339S200 <sup>(7)</sup> Com'l Only		70V7339S166 <sup>(6)</sup> Com'l & Ind		70V7339S133 Com'l & Ind		Unit
				Typ. <sup>(4)</sup>	Max.	Typ. <sup>(4)</sup>	Max.	Typ. <sup>(4)</sup>	Max.	
IDD	Dynamic Operating Current (Both Ports Active)	$\overline{CE}_L$ and $\overline{CE}_R = V_{IL}$ , Outputs Disabled, $f = f_{MAX}^{(1)}$	COM'L S	815	950	675	790	550	645	mA
			IND S	—	—	675	830	550	675	
ISB1	Standby Current (Both Ports - TTL Level Inputs)	$\overline{CE}_L = \overline{CE}_R = V_{IH}$ $f = f_{MAX}^{(1)}$	COM'L S	340	410	275	340	250	295	mA
			IND S	—	—	275	355	250	310	
ISB2	Standby Current (One Port - TTL Level Inputs)	$\overline{CE}^*A^* = V_{IL}$ and $\overline{CE}^*B^* = V_{IH}^{(3)}$ Active Port Outputs Disabled, $f = f_{MAX}^{(1)}$	COM'L S	690	770	515	640	460	520	mA
			IND S	—	—	515	660	460	545	
ISB3	Full Standby Current (Both Ports - CMOS Level Inputs)	Both Ports $\overline{CE}_L$ and $\overline{CE}_R \geq V_{DDQ} - 0.2V$ , $V_{IN} \geq V_{DDQ} - 0.2V$ or $V_{IN} \leq 0.2V$ , $f = 0^{(2)}$	COM'L S	10	30	10	30	10	30	mA
			IND S	—	—	10	40	10	40	
ISB4	Full Standby Current (One Port - CMOS Level Inputs)	$\overline{CE}^*A^* \leq 0.2V$ and $\overline{CE}^*B^* \geq V_{DDQ} - 0.2V^{(5)}$ $V_{IN} \geq V_{DDQ} - 0.2V$ or $V_{IN} \leq 0.2V$ , Active Port, Outputs Disabled, $f = f_{MAX}^{(1)}$	COM'L S	690	770	515	640	460	520	mA
			IND S	—	—	515	660	460	545	

5628 tbl 09

## NOTES:

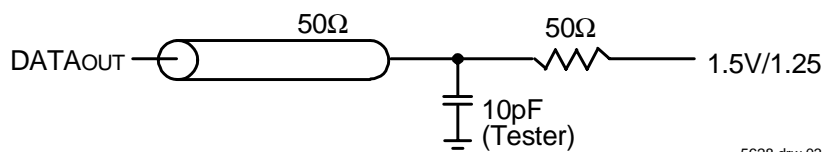
- At  $f = f_{MAX}$ , address and control lines (except Output Enable) are cycling at the maximum frequency clock cycle of  $1/t_{CYC}$ , using "AC TEST CONDITIONS" at input levels of GND to 3V.
- $f = 0$  means no address, clock, or control lines change. Applies only to input at CMOS level standby.
- Port "A" may be either left or right port. Port "B" is the opposite from port "A".
- $V_{DD} = 3.3V$ ,  $T_A = 25^\circ C$  for Typ, and are not production tested.  $I_{DDP}(f=0) = 120mA$  (Typ).
- $\overline{CE}_X = V_{IL}$  means  $\overline{CE}_{0X} = V_{IL}$  and  $CE_{1X} = V_{IH}$   
 $\overline{CE}_X = V_{IH}$  means  $\overline{CE}_{0X} = V_{IH}$  or  $CE_{1X} = V_{IL}$   
 $\overline{CE}_X \leq 0.2V$  means  $\overline{CE}_{0X} \leq 0.2V$  and  $CE_{1X} \geq V_{DDQ} - 0.2V$   
 $\overline{CE}_X \geq V_{DDQ} - 0.2V$  means  $\overline{CE}_{0X} \geq V_{DDQ} - 0.2V$  or  $CE_{1X} \leq 0.2V$   
 "X" represents "L" for left port or "R" for right port.
- 166MHz Industrial Temperature not available in BF-208 package.
- This speed grade available when  $V_{DDQ} = 3.3V$  for a specific port (i.e.,  $OPT_X = V_{IH}$ ). This speed grade is available in BC-256 only.



AC Test Conditions ( $V_{DDQ} = 3.3V/2.5V$ )

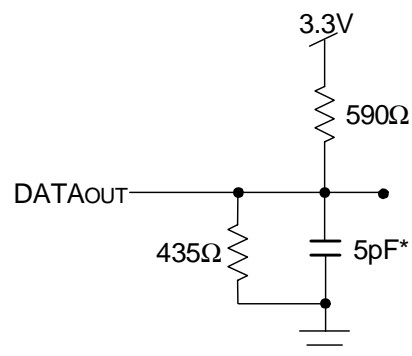
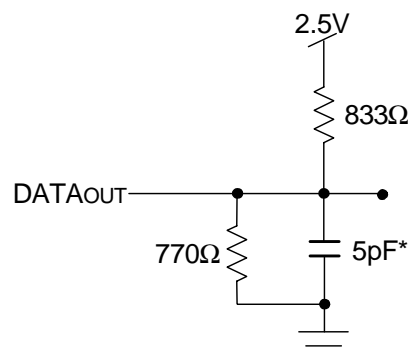
Input Pulse Levels (Address & Controls)	GND to 3.0V/GND to 2.4V
Input Pulse Levels (I/Os)	GND to 3.0V/GND to 2.4V
Input Rise/Fall Times	2ns
Input Timing Reference Levels	1.5V/1.25V
Output Reference Levels	1.5V/1.25V
Output Load	Figures 1 and 2

5628 tbl 10



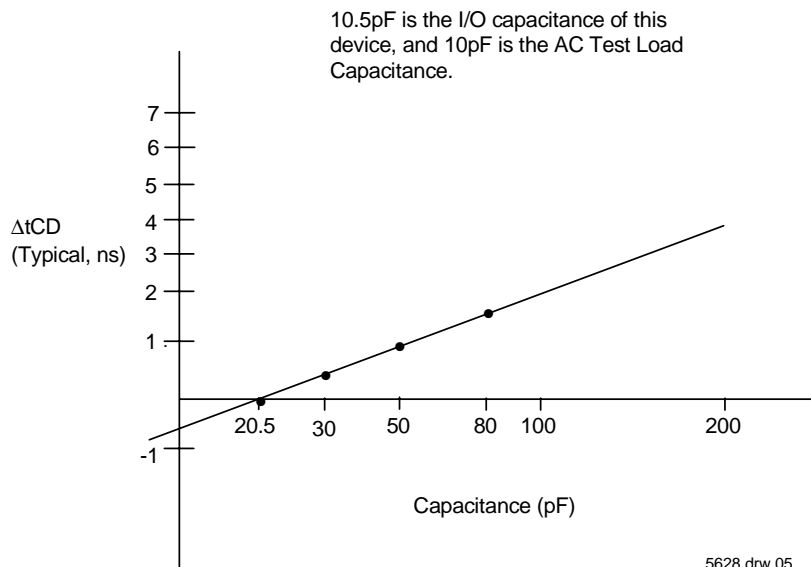
5628 drw 03

Figure 1. AC Output Test load.



5628 drw 04

Figure 2. Output Test Load  
(For  $t_{CKLZ}$ ,  $t_{CKHZ}$ ,  $t_{OLZ}$ , and  $t_{OHZ}$ ).  
\*Including scope and jig.



5628 drw 05

Figure 3. Typical Output Derating (Lumped Capacitive Load).

## AC Electrical Characteristics Over the Operating Temperature Range (Read and Write Cycle Timing)<sup>(2,3)</sup> ( $V_{DD} = 3.3V \pm 150mV$ , $T_A = 0^\circ C$ to $+70^\circ C$ )

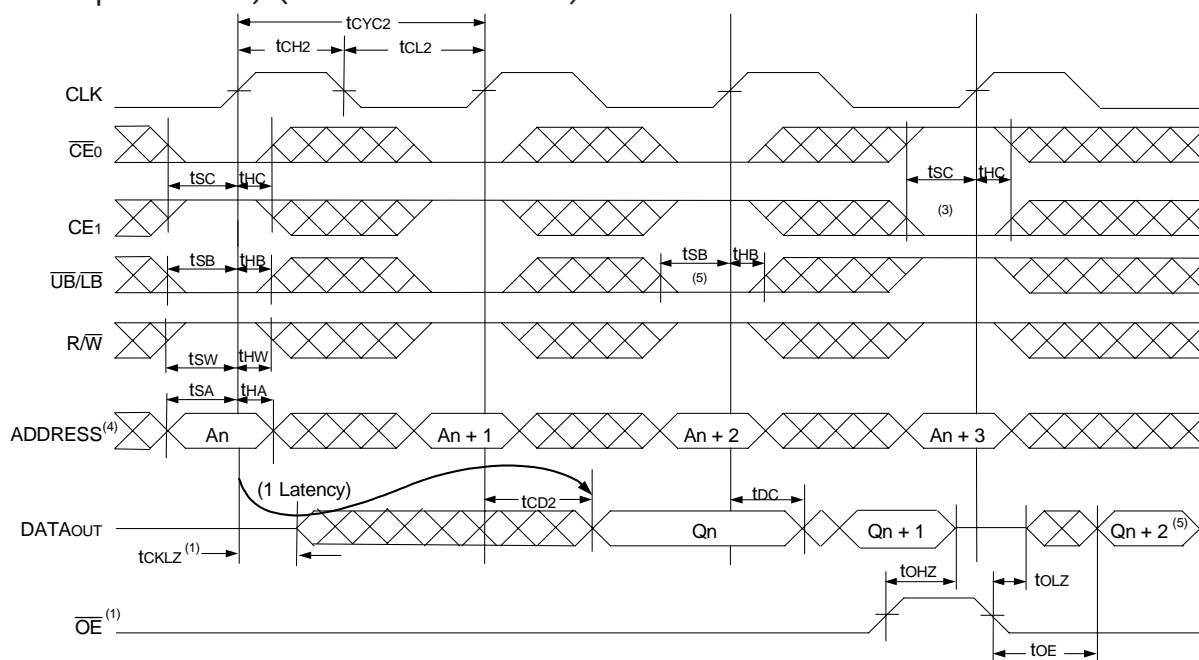
		70V7339S200 <sup>(5)</sup> Com'l Only		70V7339S166 <sup>(3,4)</sup> Com'l & Ind		70V7339S133 <sup>(3)</sup> Com'l & Ind		
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
t <sub>CYC1</sub>	Clock Cycle Time (Flow-Through) <sup>(1)</sup>	15	—	20	—	25	—	ns
t <sub>CYC2</sub>	Clock Cycle Time (Pipelined) <sup>(1)</sup>	5	—	6	—	7.5	—	ns
t <sub>CH1</sub>	Clock High Time (Flow-Through) <sup>(1)</sup>	5	—	6	—	7	—	ns
t <sub>CL1</sub>	Clock Low Time (Flow-Through) <sup>(1)</sup>	5	—	6	—	7	—	ns
t <sub>CH2</sub>	Clock High Time (Pipelined) <sup>(2)</sup>	2.0	—	2.1	—	2.6	—	ns
t <sub>CL2</sub>	Clock Low Time (Pipelined) <sup>(1)</sup>	2.0	—	2.1	—	2.6	—	ns
t <sub>r</sub>	Clock Rise Time	—	1.5	—	1.5	—	1.5	ns
t <sub>f</sub>	Clock Fall Time	—	1.5	—	1.5	—	1.5	ns
t <sub>SA</sub>	Address Setup Time	1.5	—	1.7	—	1.8	—	ns
t <sub>HA</sub>	Address Hold Time	0.5	—	0.5	—	0.5	—	ns
t <sub>SC</sub>	Chip Enable Setup Time	1.5	—	1.7	—	1.8	—	ns
t <sub>HC</sub>	Chip Enable Hold Time	0.5	—	0.5	—	0.5	—	ns
t <sub>SB</sub>	Byte Enable Setup Time	1.5	—	1.7	—	1.8	—	ns
t <sub>HB</sub>	Byte Enable Hold Time	0.5	—	0.5	—	0.5	—	ns
t <sub>SW</sub>	R/W Setup Time	1.5	—	1.7	—	1.8	—	ns
t <sub>HW</sub>	R/W Hold Time	0.5	—	0.5	—	0.5	—	ns
t <sub>SD</sub>	Input Data Setup Time	1.5	—	1.7	—	1.8	—	ns
t <sub>HD</sub>	Input Data Hold Time	0.5	—	0.5	—	0.5	—	ns
t <sub>SAD</sub>	$\overline{ADS}$ Setup Time	1.5	—	1.7	—	1.8	—	ns
t <sub>HAD</sub>	$\overline{ADS}$ Hold Time	0.5	—	0.5	—	0.5	—	ns
t <sub>SCN</sub>	$\overline{CNTEN}$ Setup Time	1.5	—	1.7	—	1.8	—	ns
t <sub>HCN</sub>	$\overline{CNTEN}$ Hold Time	0.5	—	0.5	—	0.5	—	ns
t <sub>SRPT</sub>	$\overline{REPEAT}$ Setup Time	1.5	—	1.7	—	1.8	—	ns
t <sub>HRPT</sub>	$\overline{REPEAT}$ Hold Time	0.5	—	0.5	—	0.5	—	ns
t <sub>OE</sub>	Output Enable to Data Valid	—	4.0	—	4.0	—	4.2	ns
t <sub>OLZ</sub>	Output Enable to Output Low-Z	0.5	—	0.5	—	0.5	—	ns
t <sub>OHZ</sub>	Output Enable to Output High-Z	1	3.4	1	3.6	1	4.2	ns
t <sub>CD1</sub>	Clock to Data Valid (Flow-Through) <sup>(1)</sup>	—	10	—	12	—	15	ns
t <sub>CD2</sub>	Clock to Data Valid (Pipelined) <sup>(1)</sup>	—	3.4	—	3.6	—	4.2	ns
t <sub>DC</sub>	Data Output Hold After Clock High	1	—	1	—	1	—	ns
t <sub>CKHZ</sub>	Clock High to Output High-Z	1	3.4	1	3.6	1	4.2	ns
t <sub>CKLZ</sub>	Clock High to Output Low-Z	0.5	—	0.5	—	0.5	—	ns
<b>Port-to-Port Delay</b>								
t <sub>CO</sub>	Clock-to-Clock Offset	5.0	—	6.0	—	7.5	—	ns

5628 tbl 11

**NOTES:**

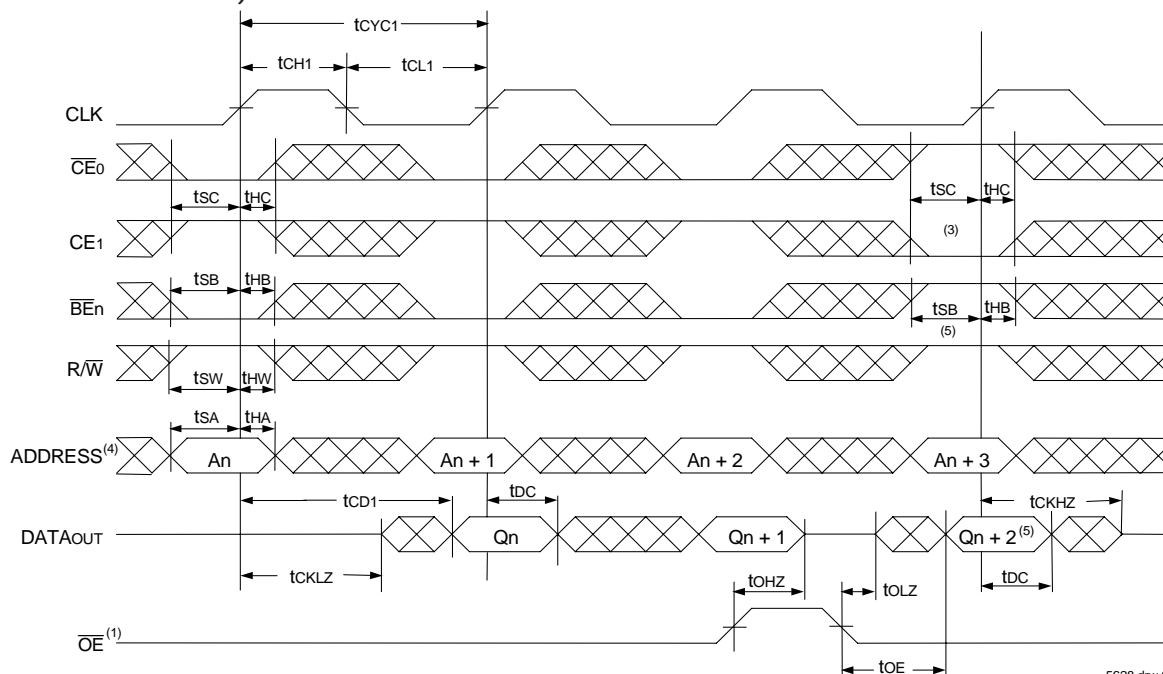
1. The Pipelined output parameters (t<sub>CYC2</sub>, t<sub>CD2</sub>) apply to either or both left and right ports when  $\overline{FT}/PIPEX = V_{IH}$ . Flow-through parameters (t<sub>CYC1</sub>, t<sub>CD1</sub>) apply when  $\overline{FT}/PIPEX = V_{IL}$  for that port.
2. All input signals are synchronous with respect to the clock except for the asynchronous Output Enable ( $\overline{OE}$ ) and  $\overline{FT}/PIPEX$ .  $\overline{FT}/PIPEX$  should be treated as a DC signal, i.e. steady state during operation.
3. These values are valid for either level of  $V_{DDQ}$  (3.3V/2.5V). See page 4 for details on selecting the desired operating voltage levels for each port.
4. 166MHz Industrial Temperature not available in BF-208 package.
5. This speed grade available when  $V_{DDQ} = 3.3V$  for a specific port (i.e.,  $OPTx = V_{IH}$ ). This speed grade available in BC-256 package only.

## Timing Waveform of Read Cycle for Pipelined Operation ( $\overline{\text{ADS}}$ Operation) ( $\overline{\text{FT}}/\text{PIPE}'\text{x}' = \text{V}_{\text{IH}}$ )<sup>(2)</sup>



5628 drw 06

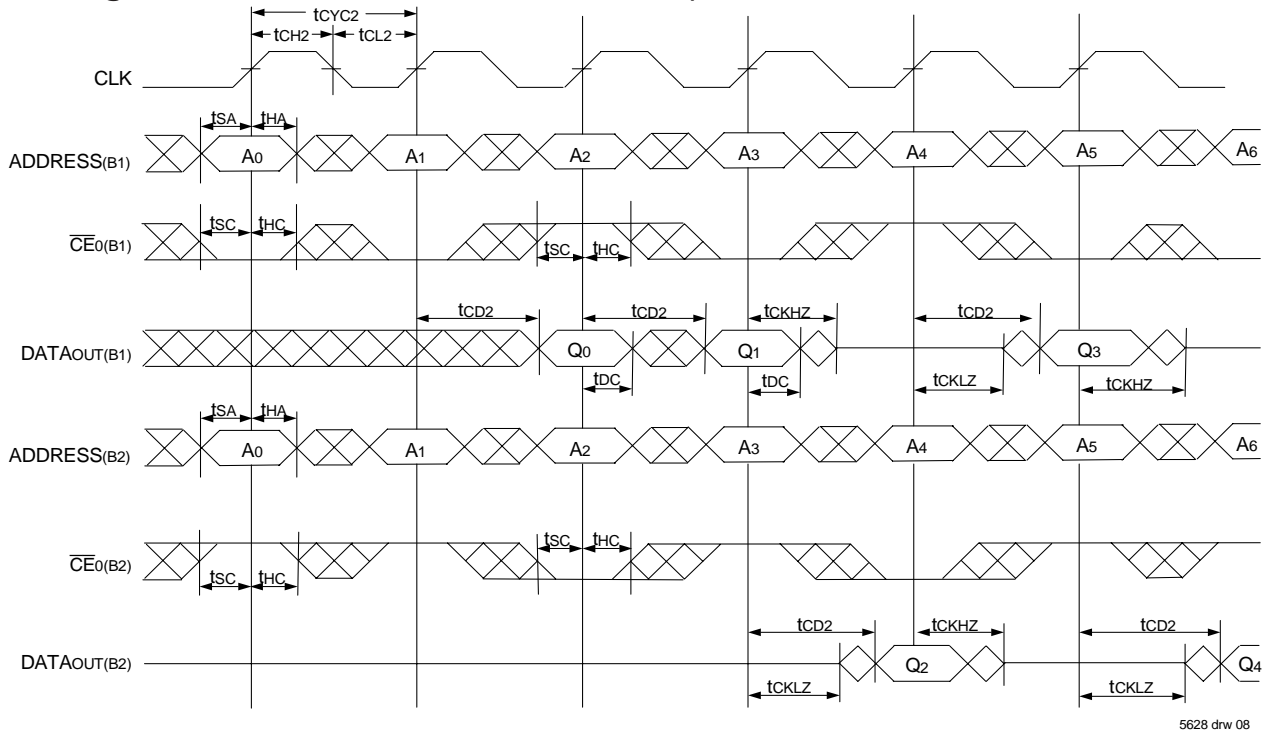
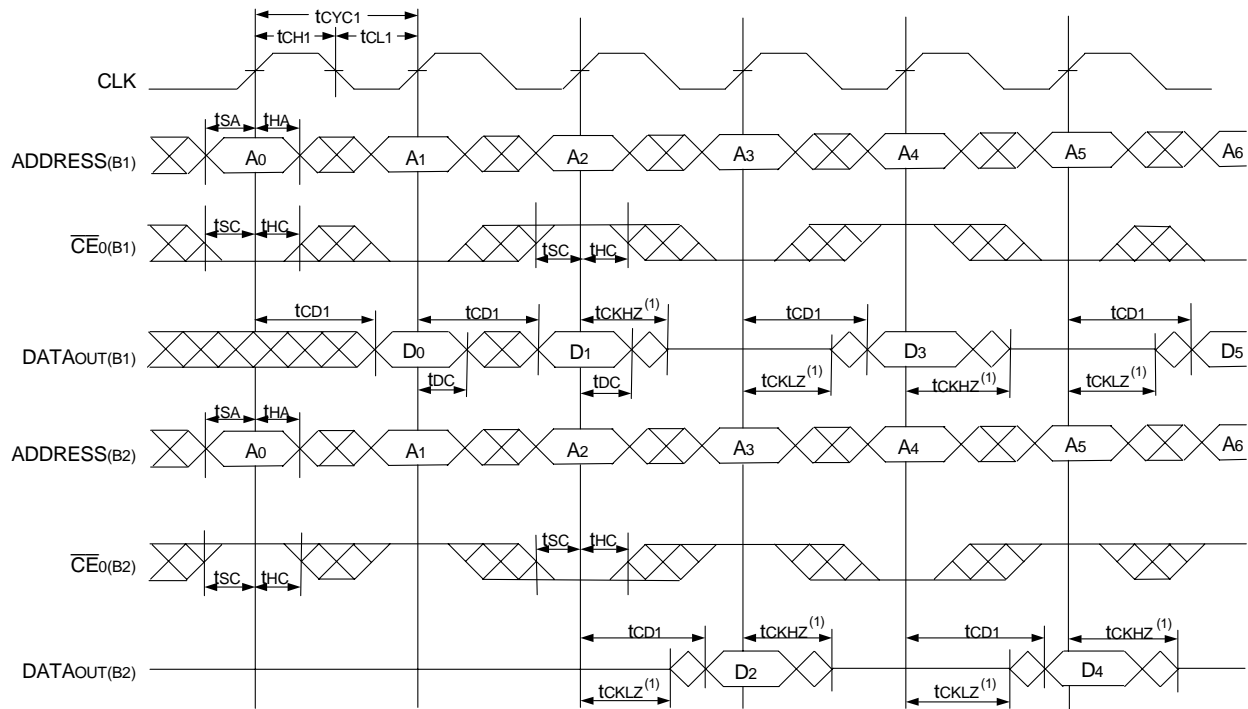
## Timing Waveform of Read Cycle for Flow-through Output ( $\overline{\text{FT}}/\text{PIPE}'\text{x}' = \text{V}_{\text{IL}}$ )<sup>(2,6)</sup>



5628 drw 07

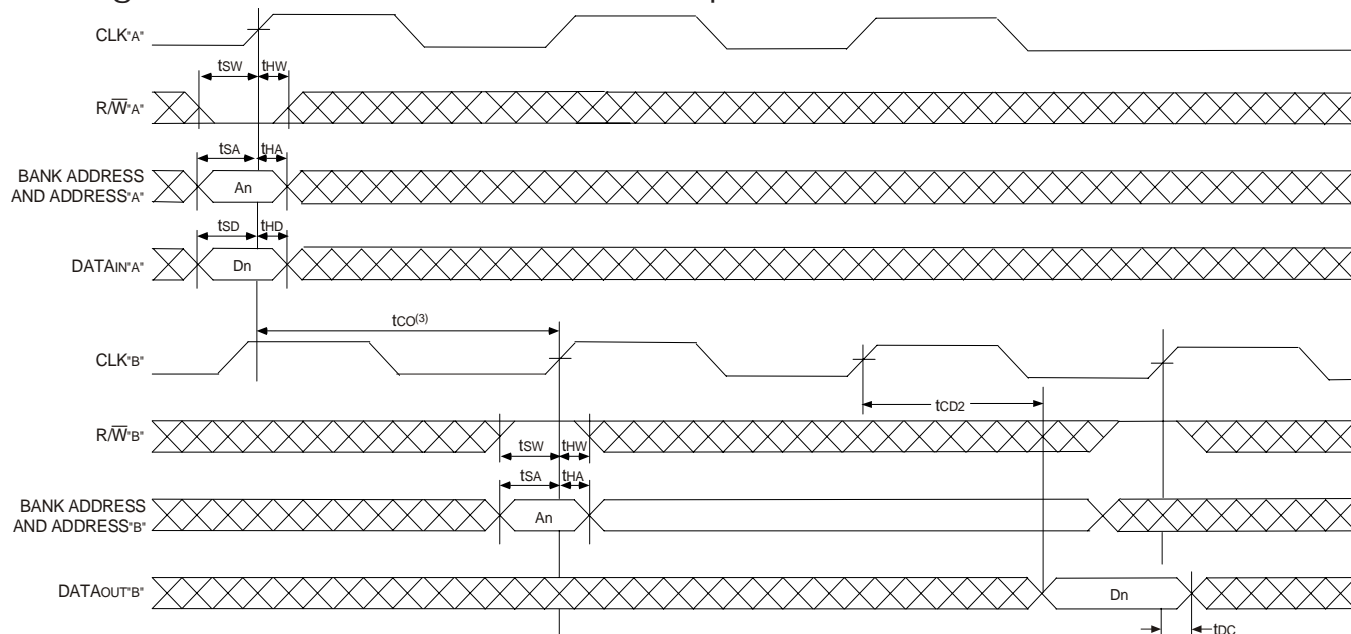
### NOTES:

1.  $\overline{\text{OE}}$  is asynchronously controlled; all other inputs are synchronous to the rising clock edge.
2.  $\overline{\text{ADS}} = \text{V}_{\text{IL}}$ ,  $\text{CNTEN}$  and  $\text{REPEAT} = \text{V}_{\text{IH}}$ .
3. The output is disabled (High-Impedance state) by  $\overline{\text{CE}}_0 = \text{V}_{\text{IH}}$ ,  $\text{CE}_1 = \text{V}_{\text{IL}}$ ,  $\overline{\text{UB}}/\overline{\text{LB}} = \text{V}_{\text{IH}}$  following the next rising edge of the clock. Refer to Truth Table 1.
4. Addresses do not have to be accessed sequentially since  $\overline{\text{ADS}} = \text{V}_{\text{IL}}$  constantly loads the address on the rising edge of the CLK; numbers are for reference use only.
5. If  $\overline{\text{UB}}/\overline{\text{LB}}$  was HIGH, then the appropriate Byte of DATAout for  $\text{Q}_{\text{n}+2}$  would be disabled (High-Impedance state).
6. "x" denotes Left or Right port. The diagram is with respect to that port.

Timing Waveform of a Multi-Device Pipelined Read<sup>(1,2)</sup>Timing Waveform of a Multi-Device Flow-Through Read<sup>(1,2)</sup>

## NOTES:

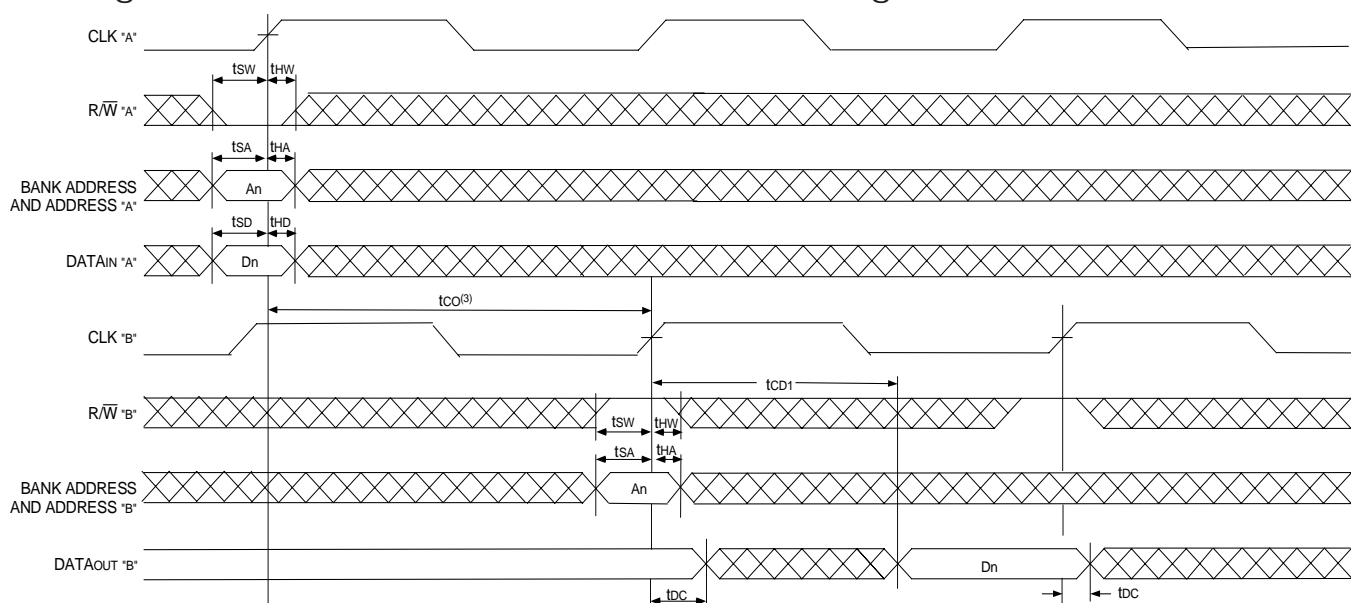
1. B1 Represents Device #1; B2 Represents Device #2. Each Device consists of one IDT70V7339 for this waveform, and are setup for depth expansion in this example. ADDRESS(B1) = ADDRESS(B2) in this situation.
2. UB/LB, OE, and ADS = VIH; CE1(B1), CE1(B2), R/W, CNTEN, and REPEAT = VIH.

Timing Waveform of Port A Write to Pipelined Port B Read<sup>(1,2,4)</sup>

5628 drw 10

## NOTES:

1.  $\overline{CE_0}$ ,  $\overline{BEn}$ , and  $\overline{ADS} = V_{IL}$ ;  $\overline{CE_1}$ ,  $\overline{CNTEN}$ , and  $\overline{REPEAT} = V_{IH}$ .
2.  $\overline{OE} = V_{IL}$  for the Right Port, which is being read from.  $\overline{OE} = V_{IH}$  for the Left Port, which is being written to.
3. If  $t_{CO} < \text{minimum specified}$ , then operations from both ports are INVALID. If  $t_{CO} \geq \text{minimum}$ , then data from Port "B" read is available on first Port "B" clock cycle (ie, time from write to valid read on opposite port will be  $t_{CO} + t_{CYC2} + t_{CD2}$ ).
4. All timing is the same for both left and right ports. Port "A" may be either left or right port. Port "B" is the opposite of Port "A".

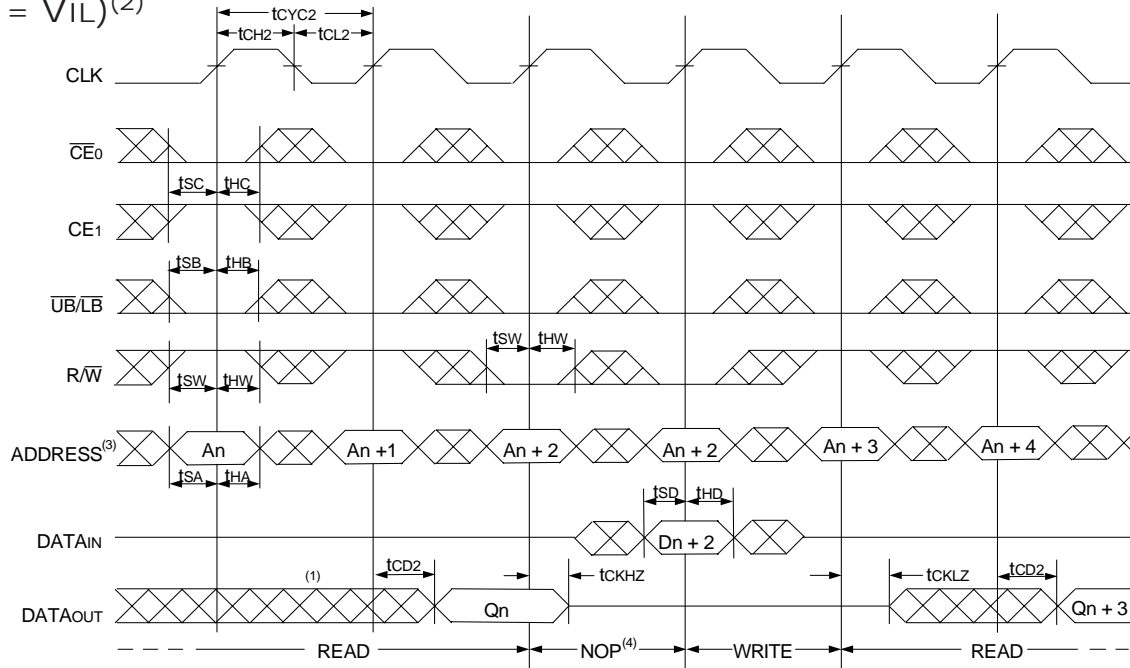
Timing Waveform with Port-to-Port Flow-Through Read<sup>(1,2,4)</sup>

5628 drw 11

## NOTES:

1.  $\overline{CE_0}$ ,  $\overline{BEn}$ , and  $\overline{ADS} = V_{IL}$ ;  $\overline{CE_1}$ ,  $\overline{CNTEN}$ , and  $\overline{REPEAT} = V_{IH}$ .
2.  $\overline{OE} = V_{IL}$  for the Right Port, which is being read from.  $\overline{OE} = V_{IH}$  for the Left Port, which is being written to.
3. If  $t_{CO} < \text{minimum specified}$ , then operations from both ports are INVALID. If  $t_{CO} \geq \text{minimum}$ , then data from Port "B" read is available on first Port "B" clock cycle (i.e., time from write to valid read on opposite port will be  $t_{CO} + t_{CD1}$ ).
4. All timing is the same for both left and right ports. Port "A" may be either left or right port. Port "B" is the opposite of Port "A".

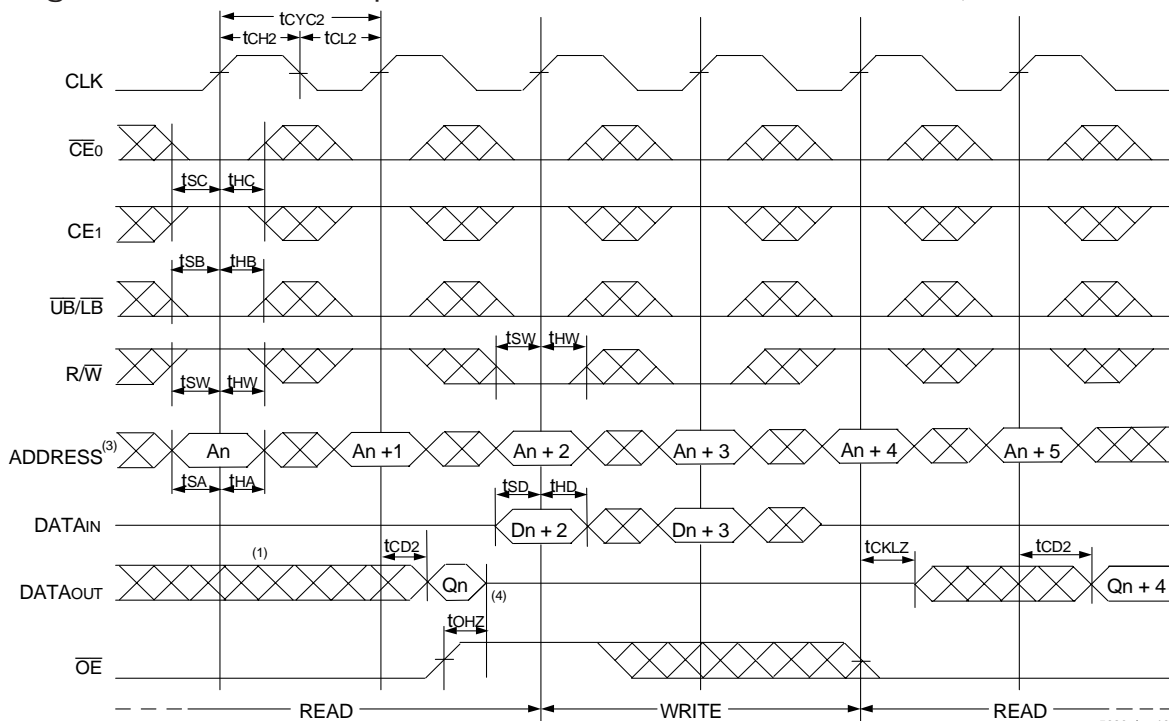
## Timing Waveform of Pipelined Read-to-Write-to-Read

 $(\overline{OE} = V_{IL})^{(2)}$ 

## NOTES:

1. Output state (High, Low, or High-impedance) is determined by the previous cycle control signals.
2.  $\overline{CE}_0$ ,  $\overline{BE}_n$ , and  $\overline{ADS} = V_{IL}$ ;  $\overline{CE}_1$ ,  $\overline{CNTEN}$ , and  $\overline{REPEAT} = V_{IH}$ . "NOP" is "No Operation".
3. Addresses do not have to be accessed sequentially since  $\overline{ADS} = V_{IL}$  constantly loads the address on the rising edge of the CLK; numbers are for reference use only.
4. "NOP" is "No Operation." Data in memory at the selected address may be corrupted and should be re-written to guarantee data integrity.

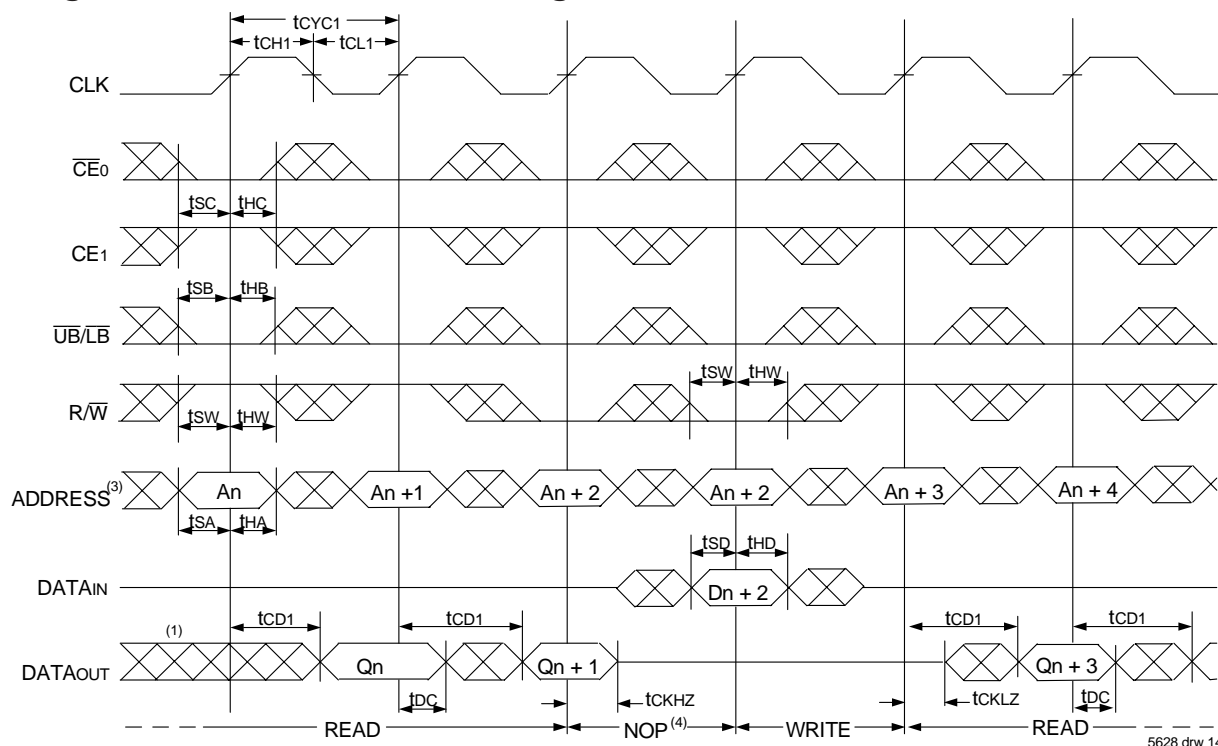
5628 drw 12

Timing Waveform of Pipelined Read-to-Write-to-Read ( $\overline{OE}$  Controlled)<sup>(2)</sup>

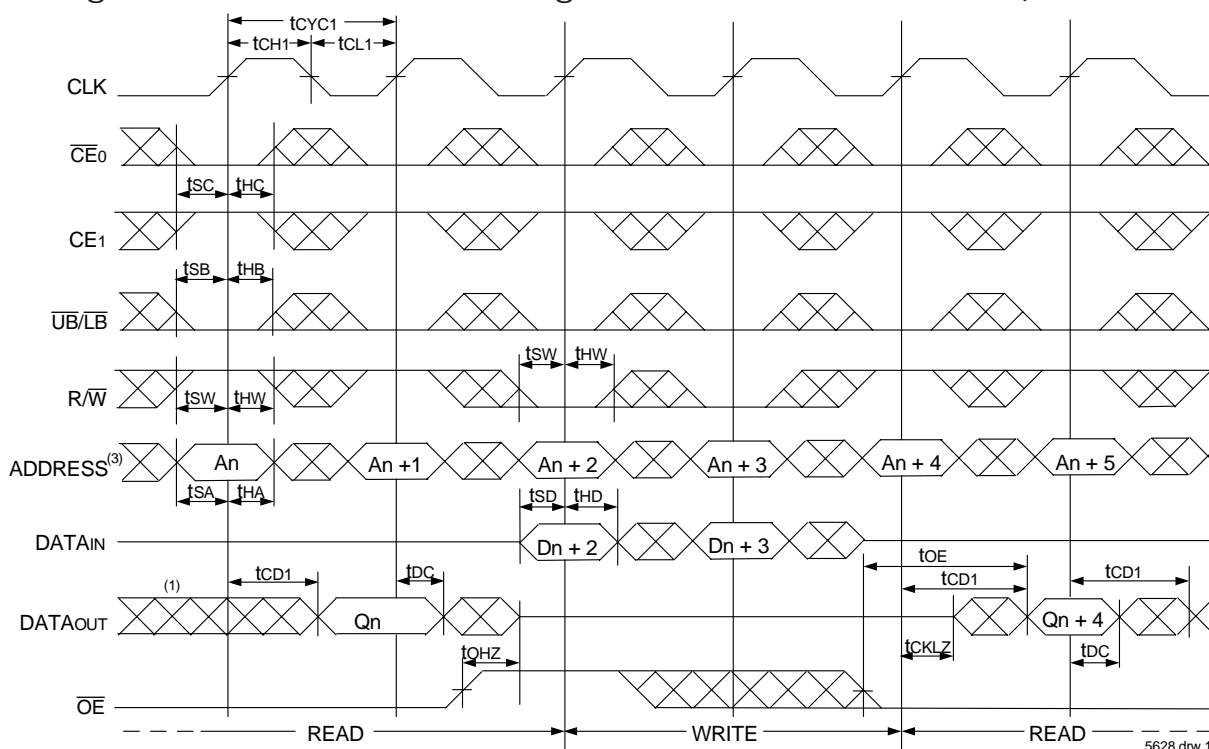
## NOTES:

1. Output state (High, Low, or High-impedance) is determined by the previous cycle control signals.
2.  $\overline{CE}_0$ ,  $\overline{UB/LB}$ , and  $\overline{ADS} = V_{IL}$ ;  $\overline{CE}_1$ ,  $\overline{CNTEN}$ , and  $\overline{REPEAT} = V_{IH}$ .
3. Addresses do not have to be accessed sequentially since  $\overline{ADS} = V_{IL}$  constantly loads the address on the rising edge of the CLK; numbers are for reference use only.
4. This timing does not meet requirements for fastest speed grade. This waveform indicates how logically it could be done if timing so allows.

5628 drw 13

Timing Waveform of Flow-Through Read-to-Write-to-Read ( $\overline{OE} = V_{IL}$ )<sup>(2)</sup>

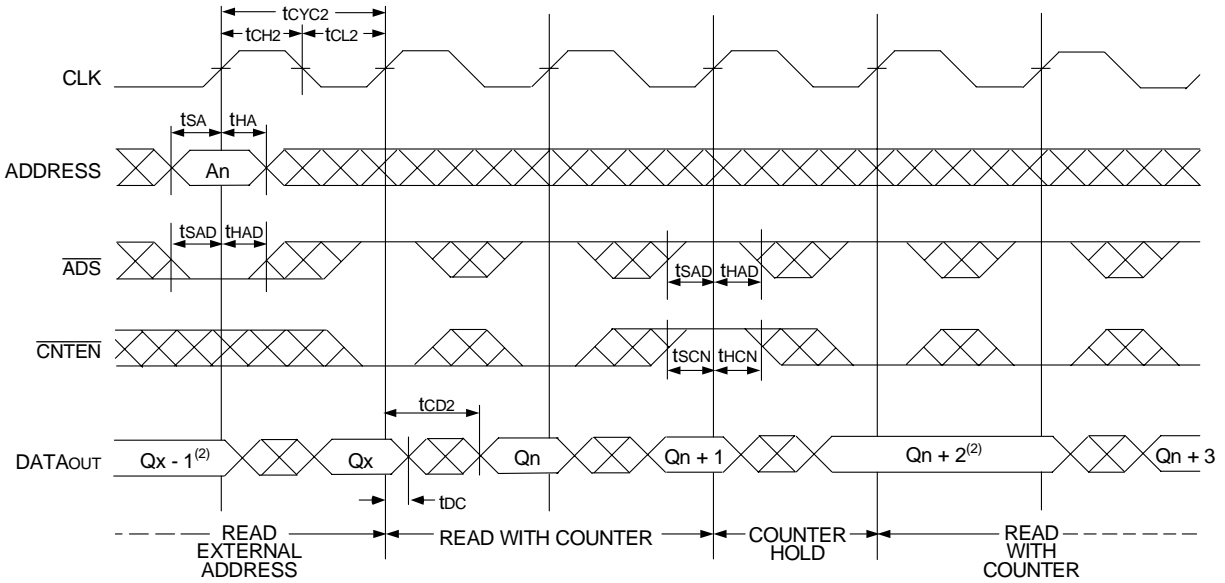
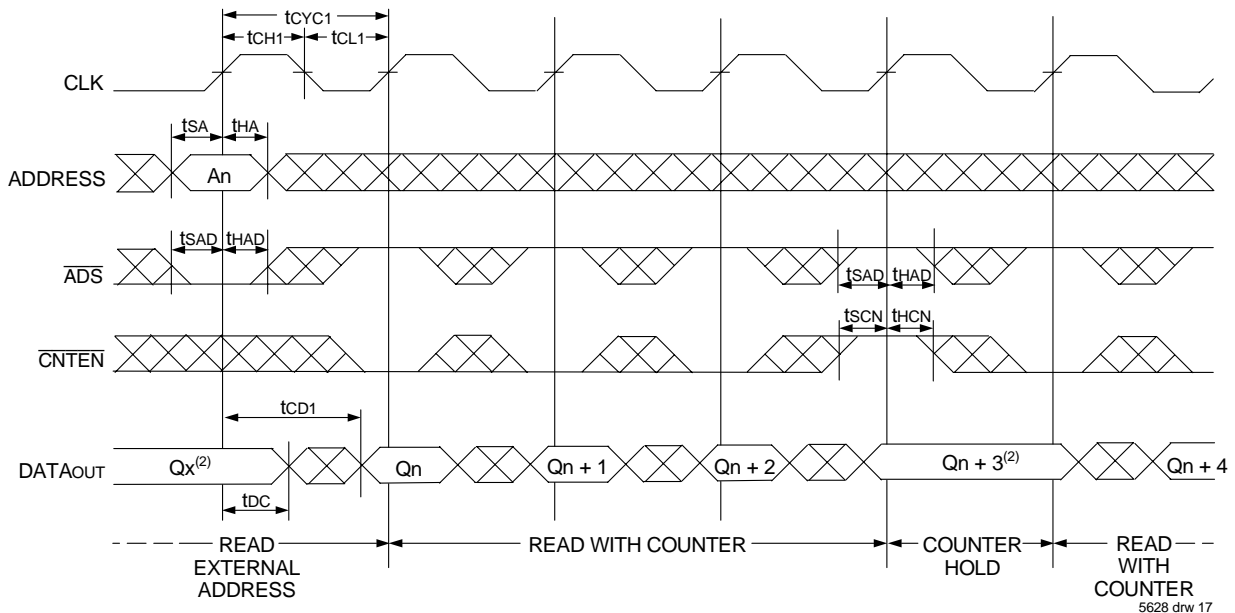
5628 drw 14

Timing Waveform of Flow-Through Read-to-Write-to-Read ( $\overline{OE}$  Controlled)<sup>(2)</sup>

5628 drw 15

## NOTES:

- Output state (High, Low, or High-impedance) is determined by the previous cycle control signals.
- $\overline{CE}_0$ ,  $\overline{UB/LB}$ , and  $\overline{ADS} = V_{IL}$ ;  $\overline{CE}_1$ ,  $\overline{CNTEN}$ , and  $\overline{REPEAT} = V_{IH}$ .
- Addresses do not have to be accessed sequentially since  $\overline{ADS} = V_{IL}$  constantly loads the address on the rising edge of the CLK; numbers are for reference use only.
- "NOP" is "No Operation." Data in memory at the selected address may be corrupted and should be re-written to guarantee data integrity.

Timing Waveform of Pipelined Read with Address Counter Advance<sup>(1)</sup>Timing Waveform of Flow-Through Read with Address Counter Advance<sup>(1)</sup>

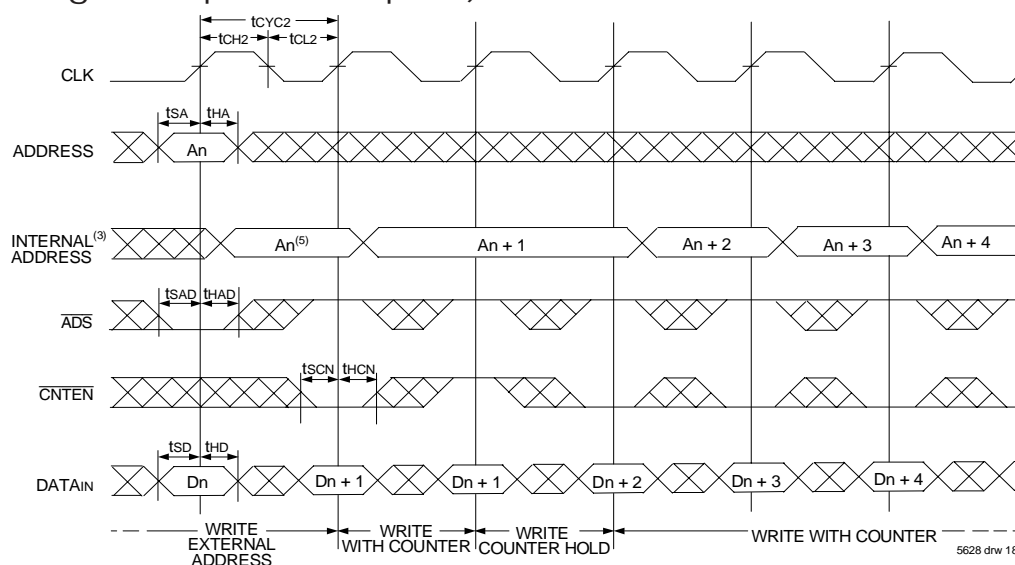
## NOTES:

1.  $\overline{CE_0}$ ,  $\overline{OE}$ ,  $\overline{UB/LB} = V_{IL}$ ;  $\overline{CE_1}$ ,  $\overline{R/W}$ , and  $\overline{REPEAT} = V_{IH}$ .

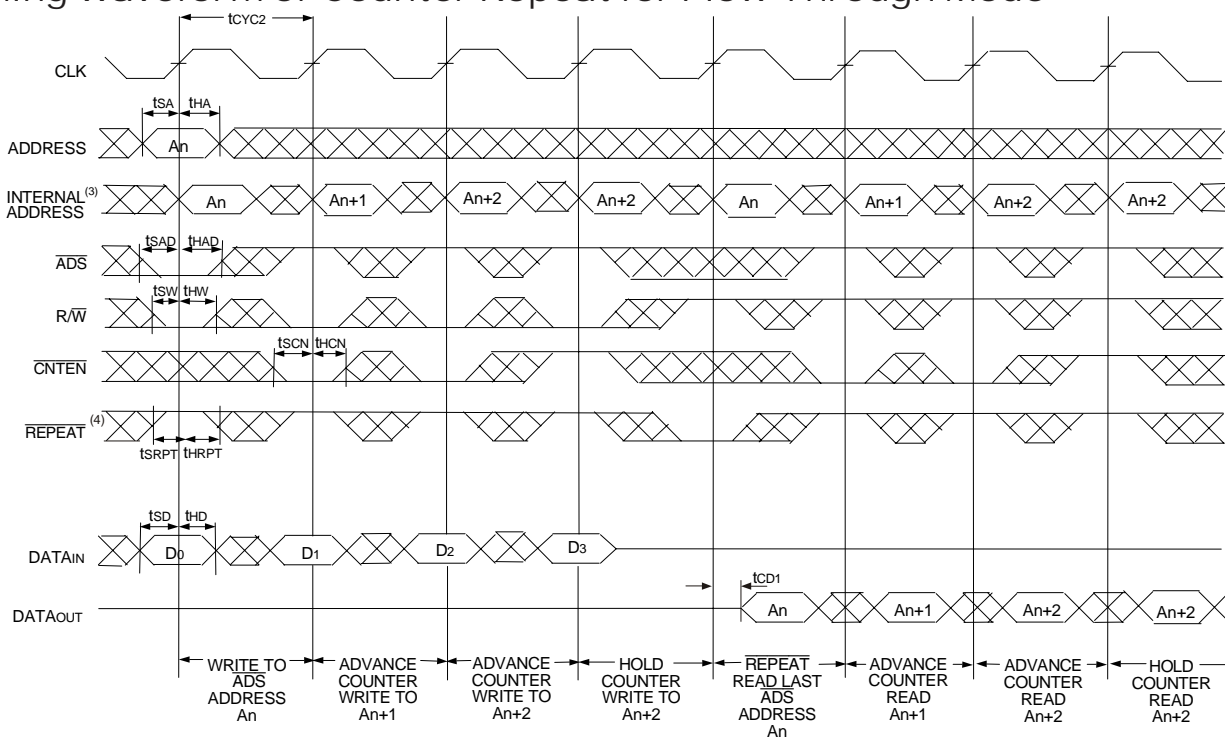
2. If there is no address change via  $\overline{ADS} = V_{IL}$  (loading a new address) or  $\overline{CNTEN} = V_{IL}$  (advancing the address), i.e.  $\overline{ADS} = V_{IH}$  and  $\overline{CNTEN} = V_{IH}$ , then the data output remains constant for subsequent clocks.



## Timing Waveform of Write with Address Counter Advance (Flow-through or Pipelined Inputs)<sup>(1,6)</sup>



## Timing Waveform of Counter Repeat for Flow Through Mode<sup>(2,6,7)</sup>



### NOTES:

1.  $\overline{CE_0}$ ,  $\overline{UB/LB}$ , and  $R/\overline{W} = V_{IL}$ ;  $CE_1$  and  $\overline{REPEAT} = V_{IH}$ .
2.  $\overline{CE_0}$ ,  $\overline{UB/LB} = V_{IL}$ ;  $CE_1 = V_{IH}$ .
3. The "Internal Address" is equal to the "External Address" when  $\overline{ADS} = V_{IL}$  and equals the counter output when  $\overline{ADS} = V_{IH}$ .
4. No dead cycle exists during  $\overline{REPEAT}$  operation. A READ or WRITE cycle may be coincidental with the counter  $\overline{REPEAT}$  cycle: Address loaded by last valid  $\overline{ADS}$  load will be accessed. For more information on  $\overline{REPEAT}$  function refer to Truth Table II.
5.  $\overline{CNTEN} = V_{IL}$  advances Internal Address from 'An' to 'An+1'. The transition shown indicates the time required for the counter to advance. The 'An+1' Address is written to during this cycle.
6. The counter includes bank address and internal address. The counter will advance across bank boundaries. For example, if the counter is in Bank 0, at address FFFh, and is advanced one location, it will move to address 0h in Bank 1. By the same token, the counter at FFFh in Bank 63 will advance to 0h in Bank 0.
7. For Pipelined Mode user should add 1 cycle latency for outputs as per timing waveform of read cycle for pipelined operations.

## Functional Description

The IDT70V7339 is a high-speed 512Kx18 (9 Mbit) synchronous Bank-Switchable Dual-Ported SRAM organized into 64 independent 8Kx18 banks. Based on a standard SRAM core instead of a traditional true dual-port memory core, this bank-switchable device offers the benefits of increased density and lower cost-per-bit while retaining many of the features of true dual-ports. These features include simultaneous, random access to the shared array, separate clocks per port, 166 MHz operating speed, full-boundary counters, and pinouts compatible with the IDT70V3319 (256Kx18) dual-port family.

The two ports are permitted independent, simultaneous access into separate banks within the shared array. Access by the ports into specific banks are controlled by the bank address pins under the user's direct control: each port can access any bank of memory with the shared array that is not currently being accessed by the opposite port (i.e.,  $BA_{0L} - BA_{5L} \neq BA_{0R} - BA_{5R}$ ). In the event that both ports try to access the same bank at the same time, neither access will be valid, and data at the two specific addresses targeted by the ports within that bank may be corrupted (in the case that either or both ports are writing) or may result in invalid output (in the case that both ports are trying to read).

The IDT70V7339 provides a true synchronous Dual-Port Static RAM interface. Registered inputs provide minimal setup and hold times on address, data and all critical control inputs.

An asynchronous output enable is provided to ease asynchronous bus interfacing. Counter enable inputs are also provided to stall the operation of the address counters for fast interleaved memory applications.

A HIGH on  $\overline{CE}_0$  or a LOW on  $CE_1$  for one clock cycle will power down the internal circuitry on each port (individually controlled) to reduce static power consumption. Dual chip enables allow easier banking of multiple IDT70V7339s for depth expansion configurations. Two cycles are required with  $\overline{CE}_0$  LOW and  $CE_1$  HIGH to read valid data on the outputs.

## Depth and Width Expansion

The IDT70V7339 features dual chip enables (refer to Truth Table I) in order to facilitate rapid and simple depth expansion with no requirements for external logic. Figure 4 illustrates how to control the various chip enables in order to expand two devices in depth.

The IDT70V7339 can also be used in applications requiring expanded width, as indicated in Figure 4. Through combining the control signals, the devices can be grouped as necessary to accommodate applications needing 36-bits or wider.

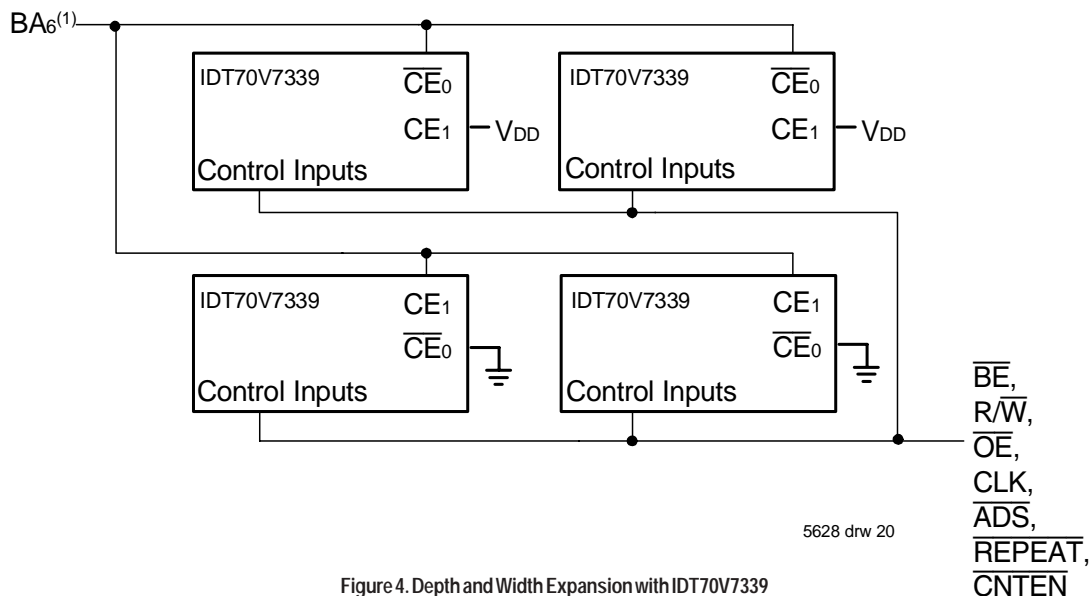
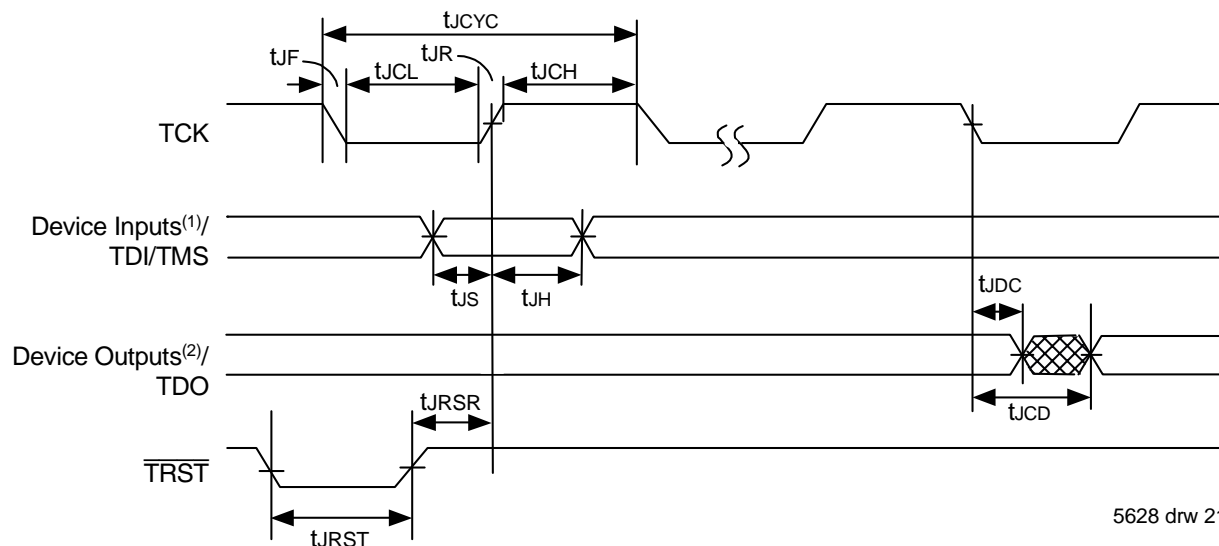


Figure 4. Depth and Width Expansion with IDT70V7339

### NOTE:

1. In the case of depth expansion, the additional address pin logically serves as an extension of the bank address. Accesses by the ports into specific banks are controlled by the bank address pins under the user's direct control: each port can access any bank of memory within the shared array that is not currently being accessed by the opposite port (i.e.,  $BA_{0L} - BA_{6L} \neq BA_{0R} - BA_{6R}$ ). In the event that both ports try to access the same bank at the same time, neither access will be valid, and data at the two specific addresses targeted by the parts within that bank may be corrupted (in the case that either or both parts are writing) or may result in invalid output (in the case that both ports are trying to read).

## JTAG Timing Specifications



5628 drw 21

Figure 5. Standard JTAG Timing

### NOTES:

1. Device inputs = All device inputs except TDI, TMS, TRST, and TCK.
2. Device outputs = All device outputs except TDO.

## JTAG AC Electrical Characteristics<sup>(1,2,3,4)</sup>

Symbol	Parameter	70V7339		
		Min.	Max.	Units
t <sub>JCYC</sub>	JTAG Clock Input Period	100	—	ns
t <sub>JCH</sub>	JTAG Clock HIGH	40	—	ns
t <sub>JCL</sub>	JTAG Clock Low	40	—	ns
t <sub>JR</sub>	JTAG Clock Rise Time	—	3 <sup>(1)</sup>	ns
t <sub>JF</sub>	JTAG Clock Fall Time	—	3 <sup>(1)</sup>	ns
t <sub>JRST</sub>	JTAG Reset	50	—	ns
t <sub>JRSR</sub>	JTAG Reset Recovery	50	—	ns
t <sub>JCD</sub>	JTAG Data Output	—	25	ns
t <sub>JDC</sub>	JTAG Data Output Hold	0	—	ns
t <sub>JS</sub>	JTAG Setup	15	—	ns
t <sub>JH</sub>	JTAG Hold	15	—	ns

5628 tbl 12

### NOTES:

1. Guaranteed by design.
2. 30pF loading on external output signals.
3. Refer to AC Electrical Test Conditions stated earlier in this document.
4. JTAG operations occur at one speed (10MHz). The base device may run at any speed specified in this datasheet.

## Identification Register Definitions

Instruction Field	Value	Description
Revision Number (31:28)	0x0	Reserved for version number
IDT Device ID (27:12)	0x301	Defines IDT part number
IDT JEDEC ID (11:1)	0x33	Allows unique identification of device vendor as IDT
ID Register Indicator Bit (Bit 0)	1	Indicates the presence of an ID register

5628 tbl 13

## Scan Register Sizes

Register Name	Bit Size
Instruction (IR)	4
Bypass (BYR)	1
Identification (IDR)	32
Boundary Scan (BSR)	Note (3)

5628 tbl 14

## System Interface Parameters

Instruction	Code	Description
EXTEST	0000	Forces contents of the boundary scan cells onto the device outputs <sup>(1)</sup> . Places the boundary scan register (BSR) between TDI and TDO.
BYPASS	1111	Places the bypass register (BYR) between TDI and TDO.
IDCODE	0010	Loads the ID register (IDR) with the vendor ID code and places the register between TDI and TDO.
HIGHZ	0100	Places the bypass register (BYR) between TDI and TDO. Forces all device output drivers to a High-Z state.
CLAMP	0011	Uses BYR. Forces contents of the boundary scan cells onto the device outputs. Places the bypass register (BYR) between TDI and TDO.
SAMPLE/PRELOAD	0001	Places the boundary scan register (BSR) between TDI and TDO. SAMPLE allows data from device inputs <sup>(2)</sup> and outputs <sup>(1)</sup> to be captured in the boundary scan cells and shifted serially through TDO. PRELOAD allows data to be input serially into the boundary scan cells via the TDI.
RESERVED	All other codes	Several combinations are reserved. Do not use codes other than those identified above.

5628 tbl 15

### NOTES:

1. Device outputs = All device outputs except TDO.
2. Device inputs = All device inputs except TDI, TMS, TRST, and TCK.
3. The Boundary Scan Descriptive Language (BSDL) file for this device is available on the IDT website ([www.idt.com](http://www.idt.com)), or by contacting your local IDT sales representative.

## Ordering Information

XXXXX	A	999	A	A	A	A		
Device Type	Power	Speed	Package		Process/ Temperature Range			
							Blank 8	Tube of Tray Tape and Reel
							Blank 1 <sup>(4)</sup>	Commercial (0°C to +70°C) Industrial (-40°C to +85°C)
							G <sup>(3)</sup>	Green
							BF BC	208-pin fpBGA (BF208) 256-pin BGA (BC256)
							200 166 133	Commercial Only <sup>(1)</sup> Commercial & Industrial <sup>(2)</sup> Commercial & Industrial
							S	Standard Power
							70V7339	9Mbit (512K x 18-Bit) Synchronous Bank-Switchable Dual-Port RAM

5628 drw 22

## NOTES:

1. Available in BC-256 package only.
2. Industrial Temperature at 166MHz not available in the BF-208 package.
3. Green parts available. For specific speeds, packages and powers contact your local sales office.
4. Contact your local sales office for industrial temp range for other speeds, packages and powers

LEAD FINISH (SnPb) parts are in EOL process. Product Discontinuation Notice - PDN# SP-17-02

## Datasheet Document History

01/05/00:	Initial Public Offering
06/20/01:	Page 1 Added JTAG information for TQFP package Page 4 & 22 Changed TQFP package from DA to DD Corrected Pin number on TQFP package from 100 to 110 Page 20 Increased $t_{CD}$ from 20ns to 25ns
08/06/01:	Page 4 Changed body size for DD package from 22mm x 22mm x 1.6mm to 20mm x 20mm x 1.4mm Page 9 Changed $I_{SB3}$ values for commercial and industrial DC Electrical Characteristics
11/20/01:	Page 2, 3 & 4 Added date revision for pin configurations Page 11 Changed $t_{OE}$ value in AC Electrical Characteristics, please refer to Errata #SMEN-01-05 Page 1 & 22 Replaced $\text{TM}$ logo with $\text{®}$ logo
03/18/02:	Page 1, 9, 11 & 22 Added 200MHZ specification Page 9 Tightened power numbers in DC Electrical Characteristics Page 14 Changed waveforms to show INVALID operation if $t_{CO} <$ minimum specified Page 1 - 22 Removed "Preliminary" status
12/04/02:	Page 9, 11 & 22 Designated 200Mhz speed grade in BC-256 package only
01/16/04:	Page 11 Added byte enable setup time and byte enable hold time parameters and values to all speed grades in the AC Electrical Characteristics Table
07/25/08:	Page 9 Corrected a typo in the DC Chars table
01/29/09:	Page 22 Removed "IDT" from orderable part number

## Datasheet Document History (con't)

04/20/10: Page 1 Added green availability to features  
Page 21 Added green indicator to ordering information  
Removed the DD 144-pin TQFP (DD-144) Thin Quad Flatpack per PDN: F-08-01

08/11/15: Page 2 & 3 Removed the date from all of the pin configurations BF208 & BC256  
Page 21 Added T&R indicator and updated footnotes for Ordering Information

06/22/18: Product Discontinuation Notice - PDN# SP-17-02  
Last time buy expires June 15, 2018

**CORPORATE HEADQUARTERS**

6024 Silver Creek Valley Road  
San Jose, CA 95138

**for SALES:**

800-345-7015 or 408-284-8200  
fax: 408-284-2775  
[www.idt.com](http://www.idt.com)

**for Tech Support:**

408-284-2794  
[DualPortHelp@idt.com](mailto:DualPortHelp@idt.com)

The IDT logo is a registered trademark of Integrated Device Technology, Inc.

# Mouser Electronics

Authorized Distributor

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

## IDT (Integrated Device Technology):

[70V7339S166BC8](#) [70V7339S166BF8](#) [70V7339S166BCGI](#) [70V7339S166BF](#) [70V7339S166BC](#) [70V7339S166BFG8](#)  
[70V7339S166BCI8](#) [70V7339S133BCI](#) [70V7339S133BFI](#) [70V7339S200BC](#) [70V7339S166BCI](#) [70V7339S166BFG](#)  
[70V7339S133BFI8](#) [70V7339S133BCI8](#) [70V7339S200BC8](#) [70V7339S133BF](#) [70V7339S133BC](#) [70V7339S133BC8](#)  
[70V7339S133BF8](#) [70V7339S200BCG](#)



**Стандарт  
Электрон  
Связь**

Мы молодая и активно развивающаяся компания в области поставок электронных компонентов. Мы поставляем электронные компоненты отечественного и импортного производства напрямую от производителей и с крупнейших складов мира.

Благодаря сотрудничеству с мировыми поставщиками мы осуществляем комплексные и плановые поставки широчайшего спектра электронных компонентов.

Собственная эффективная логистика и склад в обеспечивает надежную поставку продукции в точно указанные сроки по всей России.

Мы осуществляем техническую поддержку нашим клиентам и предпродажную проверку качества продукции. На все поставляемые продукты мы предоставляем гарантию .

Осуществляем поставки продукции под контролем ВП МО РФ на предприятия военно-промышленного комплекса России , а также работаем в рамках 275 ФЗ с открытием отдельных счетов в уполномоченном банке. Система менеджмента качества компании соответствует требованиям ГОСТ ISO 9001.

Минимальные сроки поставки, гибкие цены, неограниченный ассортимент и индивидуальный подход к клиентам являются основой для выстраивания долгосрочного и эффективного сотрудничества с предприятиями радиоэлектронной промышленности, предприятиями ВПК и научно-исследовательскими институтами России.

С нами вы становитесь еще успешнее!

**Наши контакты:**

**Телефон:** +7 812 627 14 35

**Электронная почта:** [sales@st-electron.ru](mailto:sales@st-electron.ru)

**Адрес:** 198099, Санкт-Петербург,  
Промышленная ул, дом № 19, литера Н,  
помещение 100-Н Офис 331